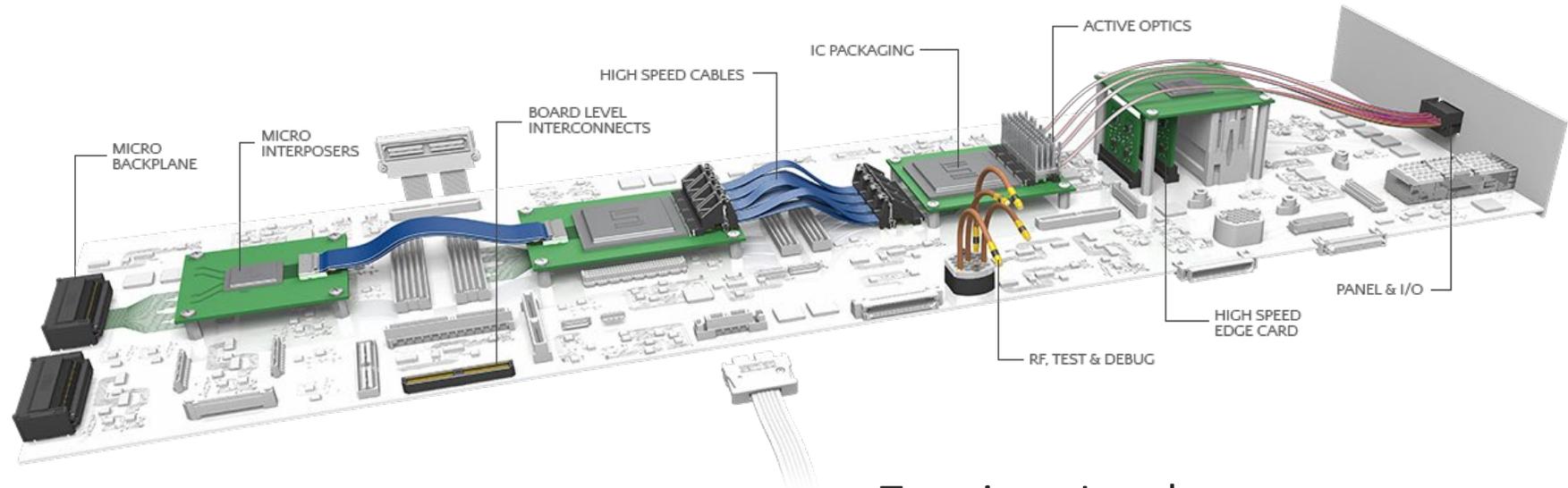


Following the 'Signals' – Overcoming Challenges from Transistor to AI Data Centers with EDA, CAE, and AI Solutions

Alexander Petr
Sr. Director, Keysight R&D

Agenda

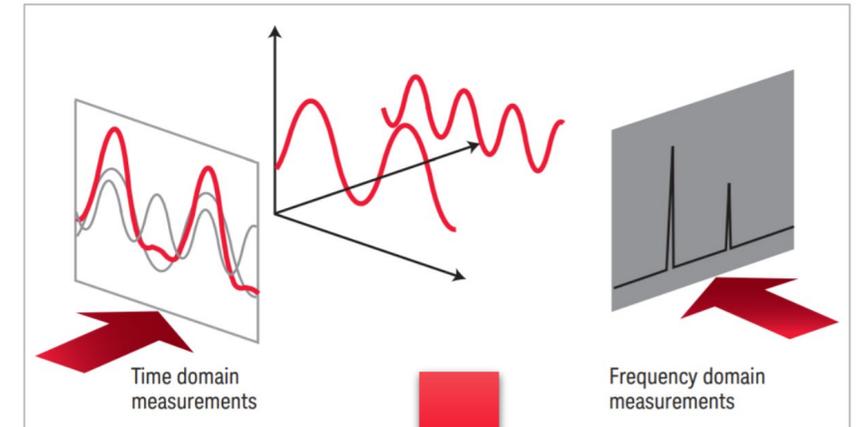
Follow the 'Signal'



- Transistor Level
- Circuit Level
- System Level
- Package/Board/3DIC
- Datacenter Level
- Network Level

Definition of 'Signal'

- An electrical signal is a form of energy transmission through electric charges
 - movement or flow of electrical energy, carrying information from one point to another
- **Analog signals:**
 - vary continuously in time and amplitude
- **Digital signals:**
 - discrete values, typically representing binary '0s' and '1s'



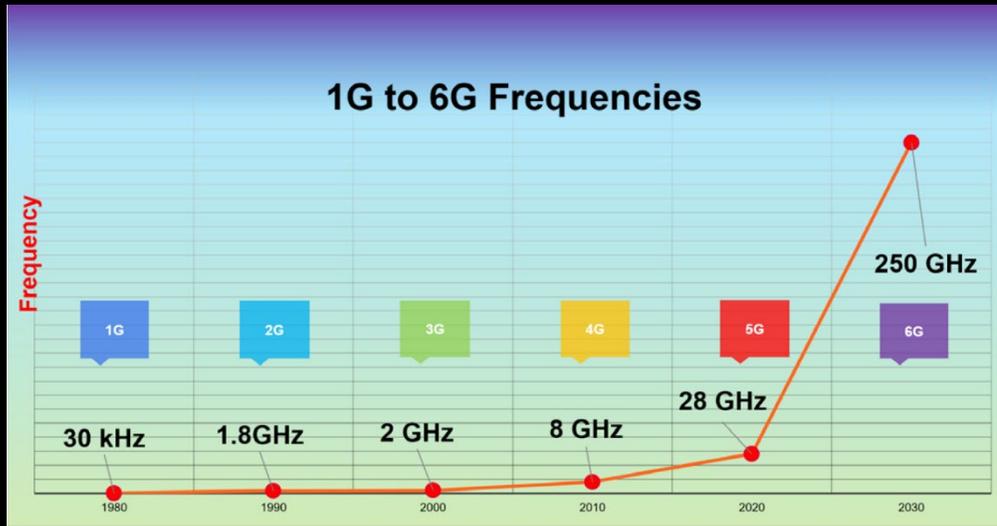
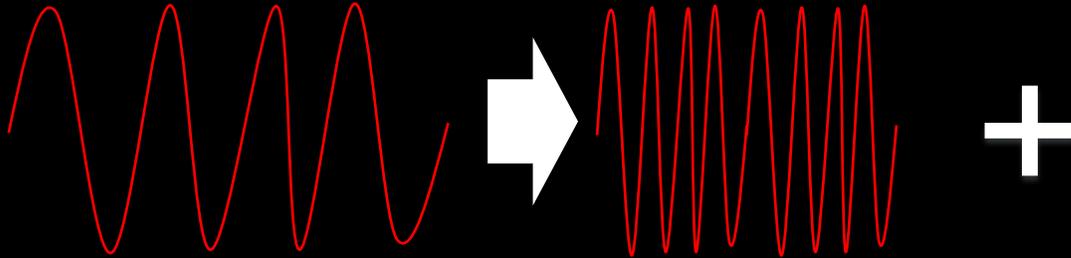
Original Signal

Quantized Signal

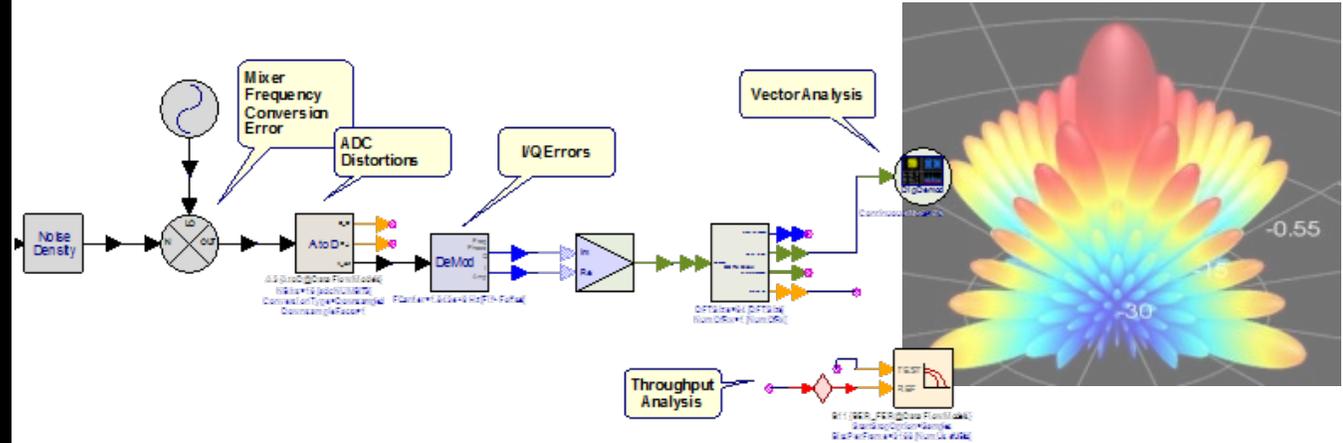
Quantization noise

High Frequencies Drive

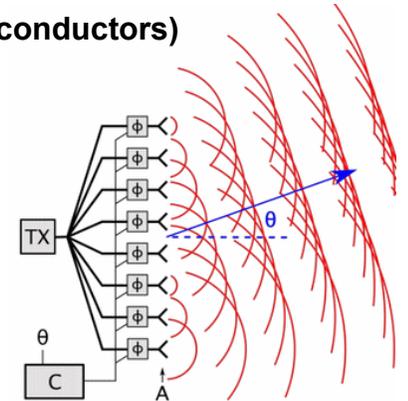
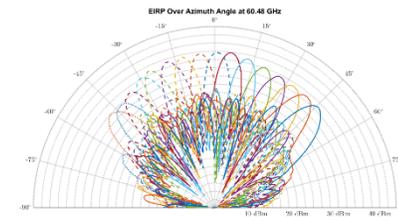
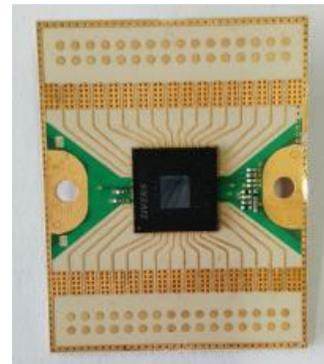
...Higher Frequencies



New Engineering Challenges

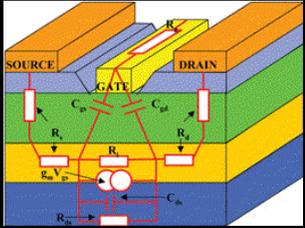


WLAN 802.11ad transceiver (courtesy of Siivers Semiconductors)

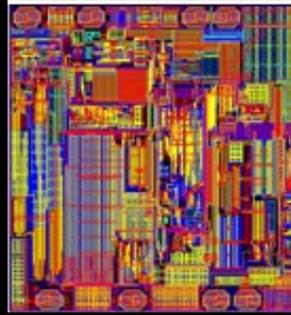


[Wikipedia](https://en.wikipedia.org/wiki/WLAN_802.11ad)

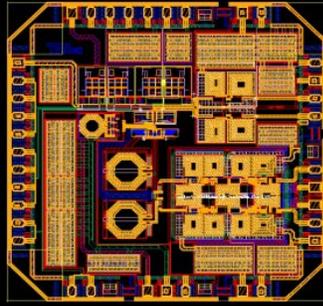
Signal challenges at every layer of the Technology Stack



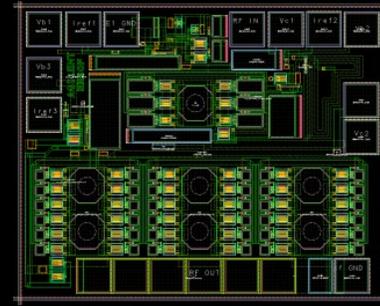
Primitive Devices



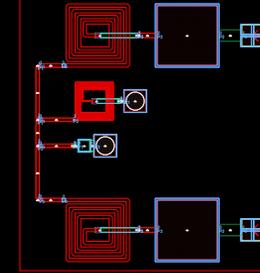
Analog / Mixed Signal IC (Si)



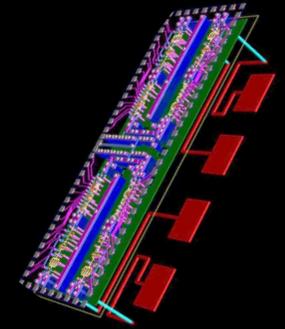
RFIC (Silicon)



RFIC (Non-Si)

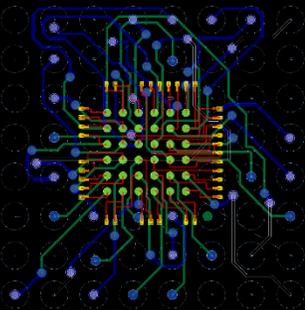


MMIC

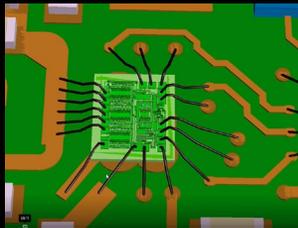


3DIC / 3DHI

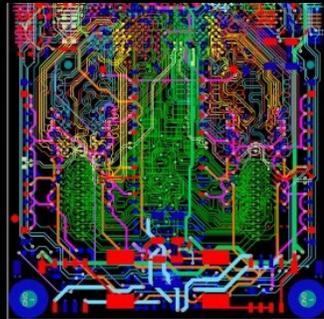
Signal complexity increases



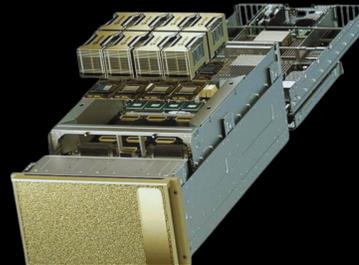
Small Scale Package



Wiring



Large Scale PCB



System



Server



Network

Transistor Level

Key Challenges

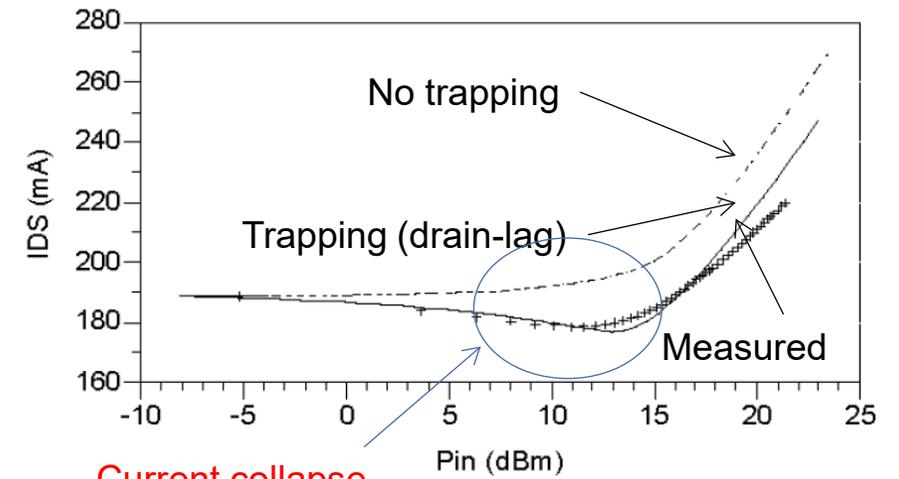
- Smaller technology nodes, higher frequencies, and new materials make model **extraction increasingly intricate** and data-intensive
- Every new technologies exhibits new artifacts and physical effects, **model accuracy increasingly difficult** for a large performance range
- More demand for **efficient Power PAs** for RF & MMIC (e.g. Gallium Nitride (GaN))



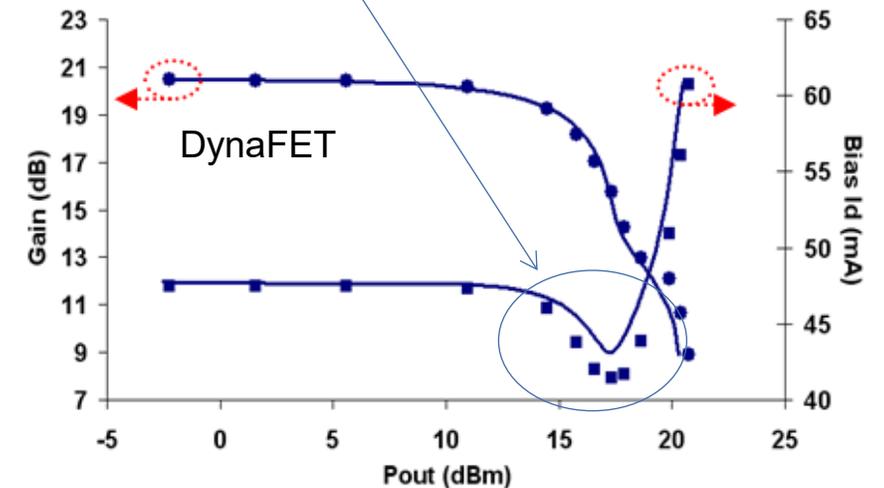
Transistor Level - Customer Problem

PA design accuracy challenges – e.g. GaN

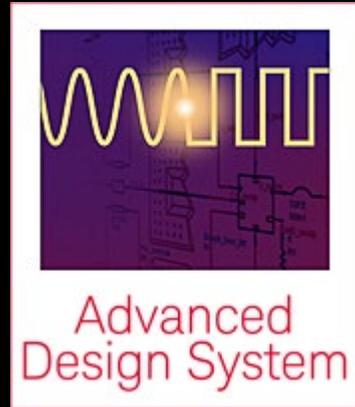
- **New effects causing model inaccuracies**
 - Gain Compression, PAE, Intermodulation and Load Pull data show inaccurate behaviors in PDKs vs. Designs
 - Large discrepancy between DC, small and large signal results also typical in PDKs.
 - Especially true for III-V technologies like GaN → dynamic effects of trapping are still not accurately modeled by existing compact models
 - Some models like Angelov for GaN may allow some trade-off of DC, S-parameter and large-signal at specific bias-points
- Inability to predict current collapse (increase of PAE), knee-effect / drain-lag → reduction of the RF output signal as input power increase



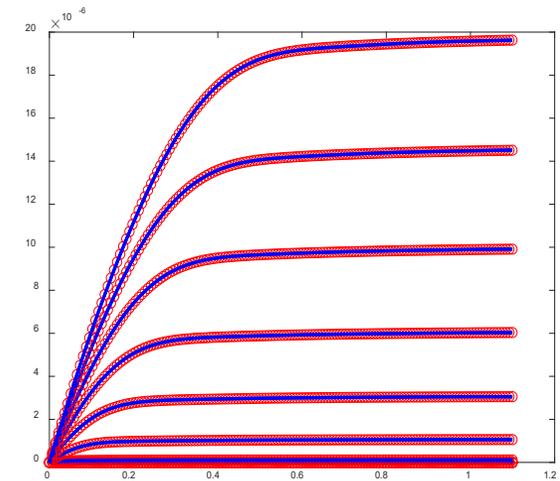
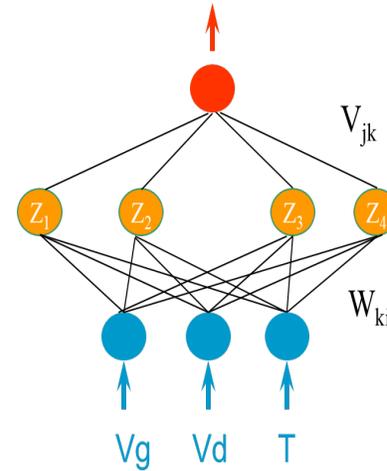
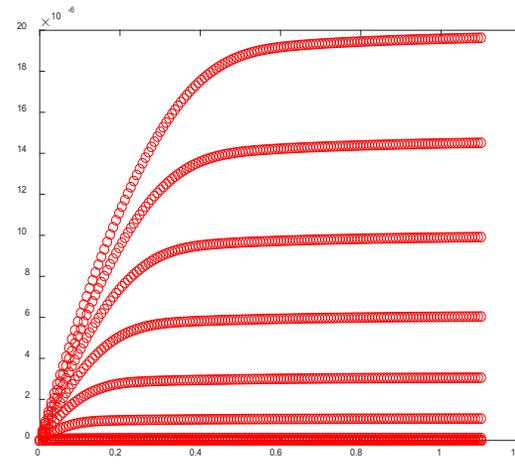
Current collapse



Transistor Level – Data driven Model solutions



$$I_d = I_d^{ANN} (Vg, Vd, T, W, L)$$



Data



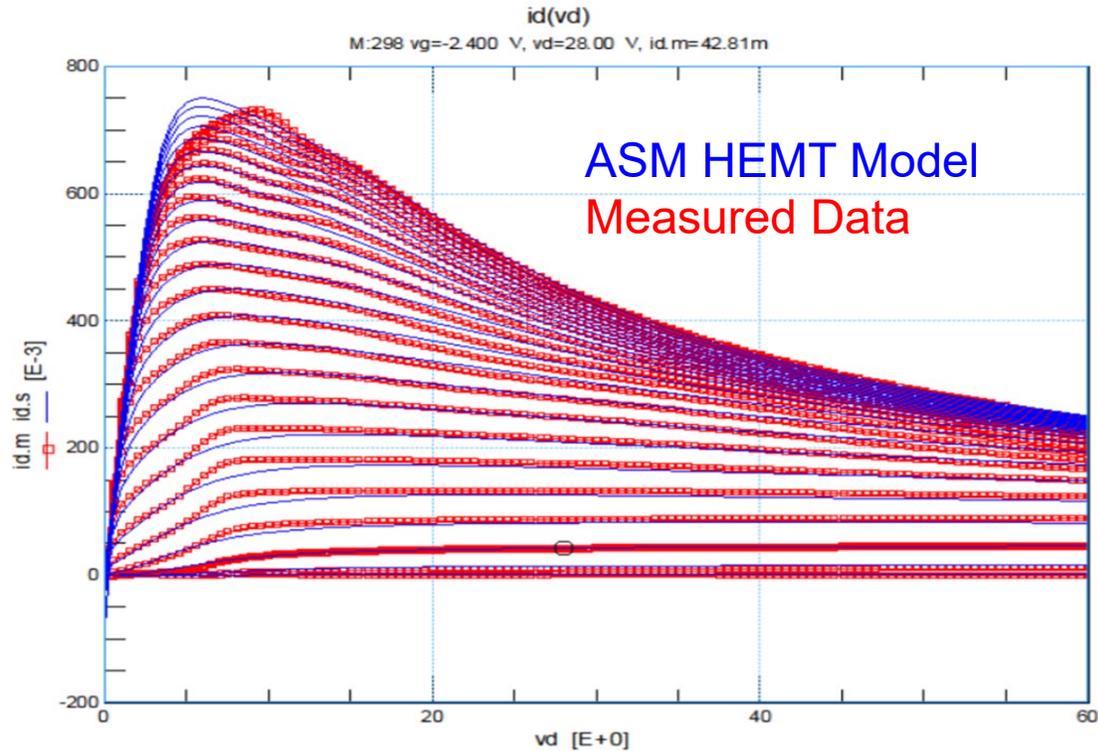
ANN



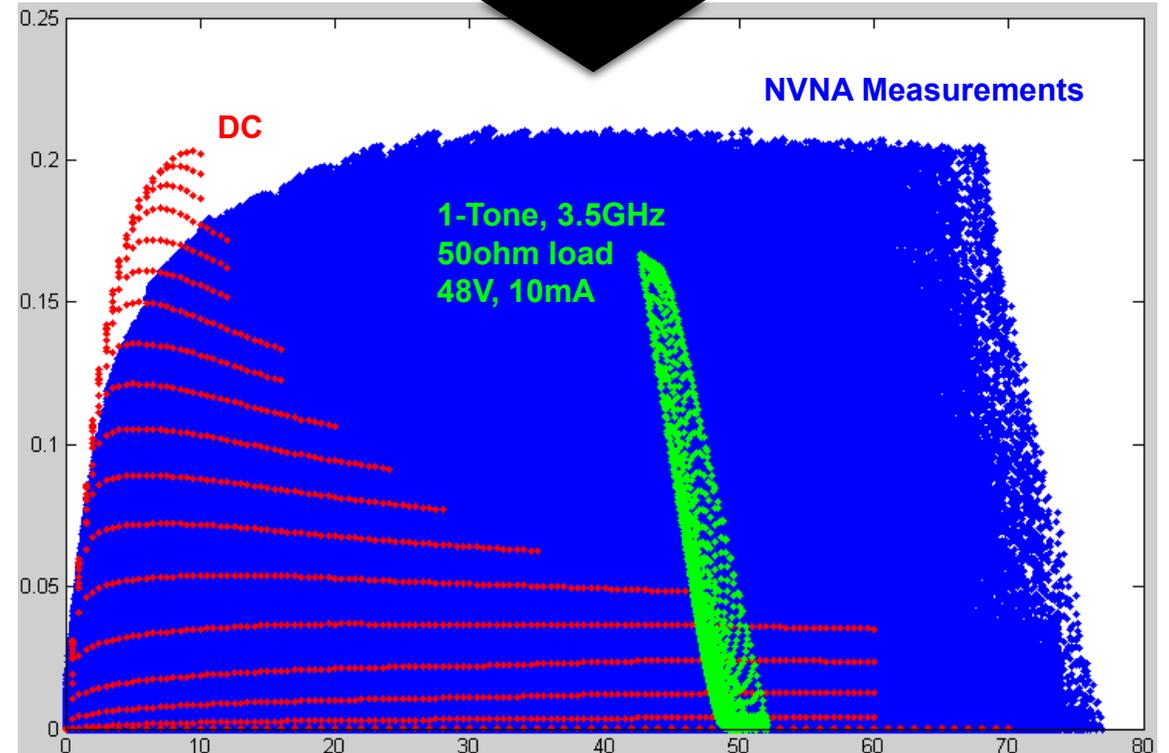
Model

“If the design doesn’t work, it’s the **Models** fault”

Much faster I-V modeling with improved accuracy



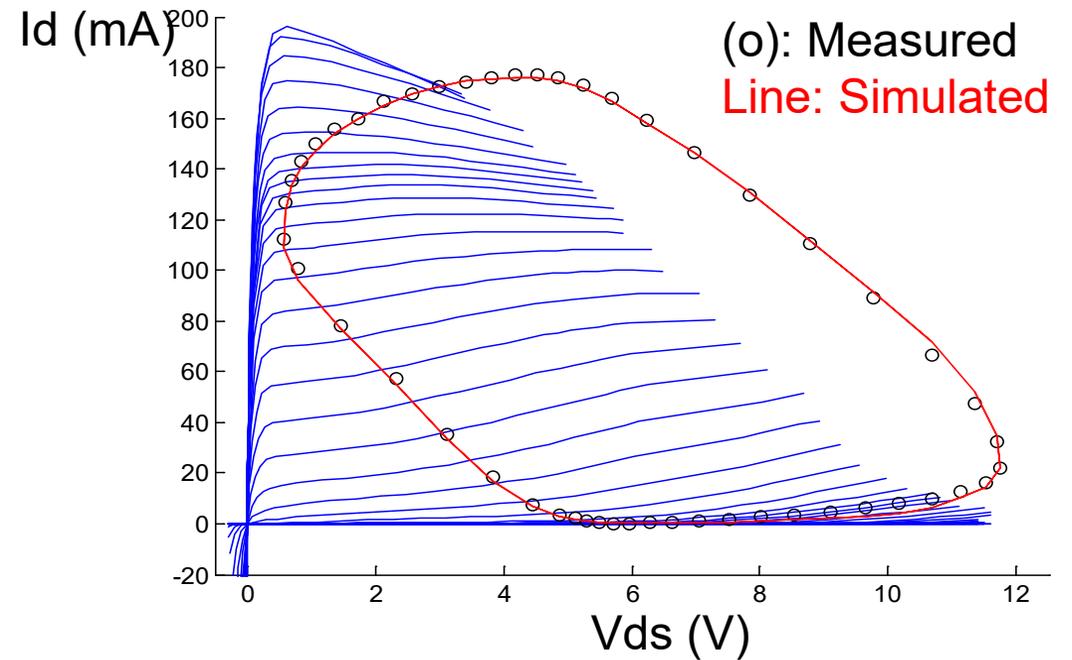
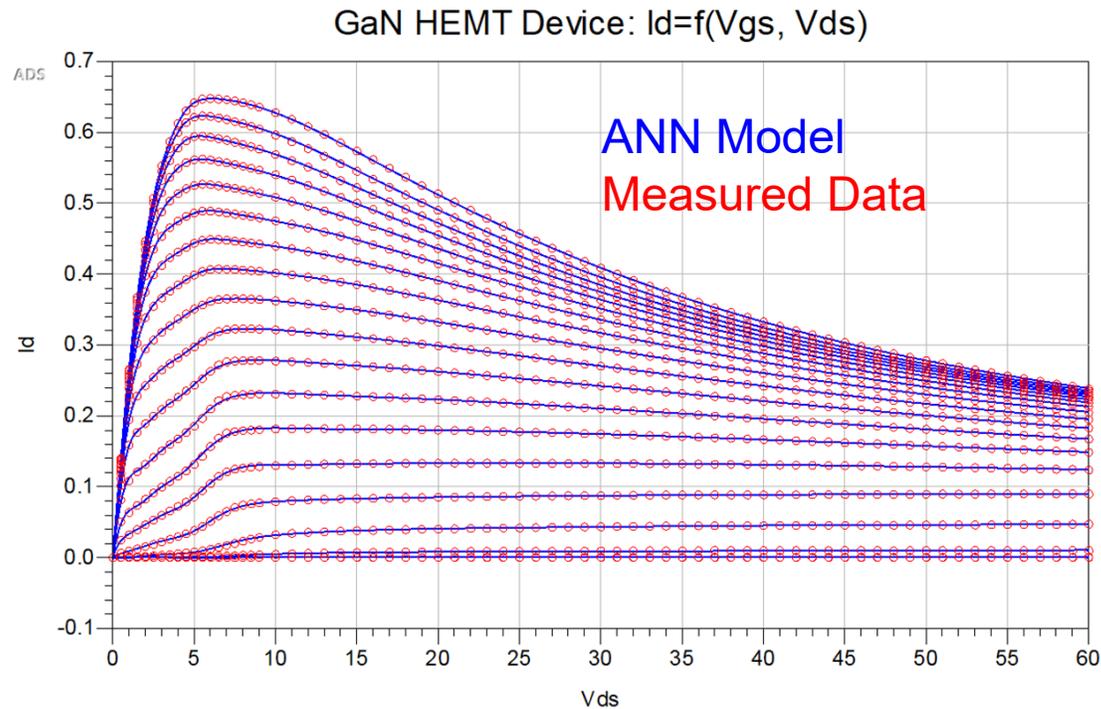
$$I_d = \frac{\mu_{eff}}{\sqrt{1 + \theta_{sat}^2 \psi_{ds}^2}} \frac{W}{L} C_g N_f \left[V_{go} - \left(\frac{\psi_s + \psi_d}{2} \right) + V_{th} \right] \psi_{ds} (1 + \lambda V_{ds})$$



J. Xu, S. Halder, F. Kharabi, J. McMacken, J. Gering, and D. E. Root, ARFTG Conf. June, 2014, Tampa

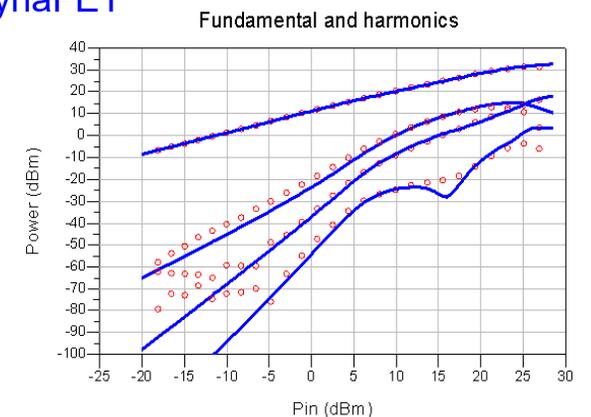
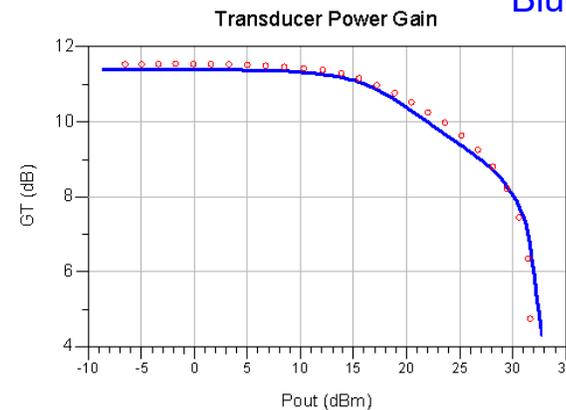
“If the design doesn’t work, it’s the **Models** fault”

Much faster I-V modeling with improved accuracy



Red: Measured
Blue: DynaFET

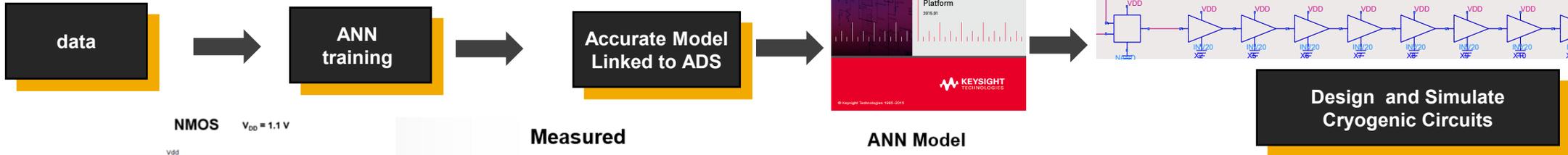
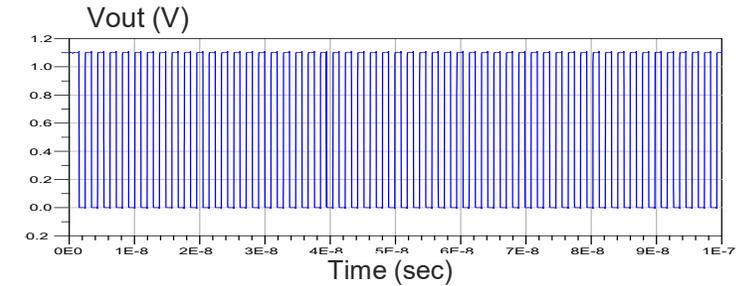
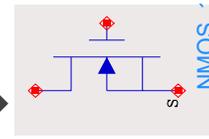
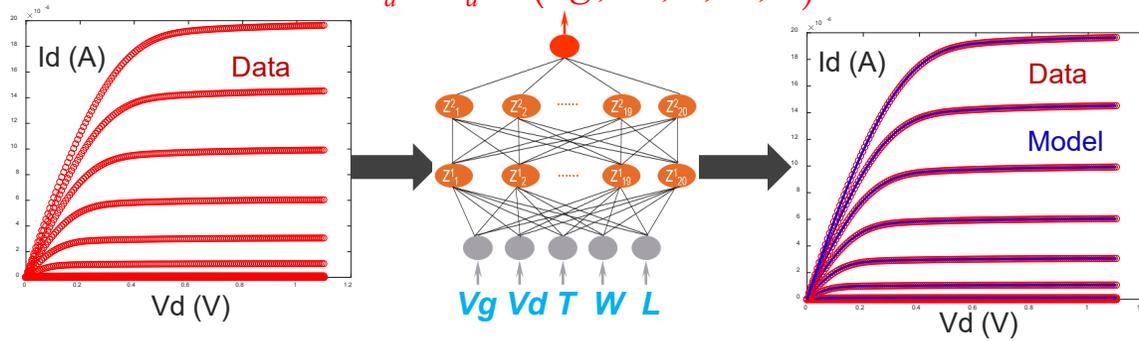
“I just spent **four months** trying to extract the ASM model to the same data set and you got better results in **two minutes!**”



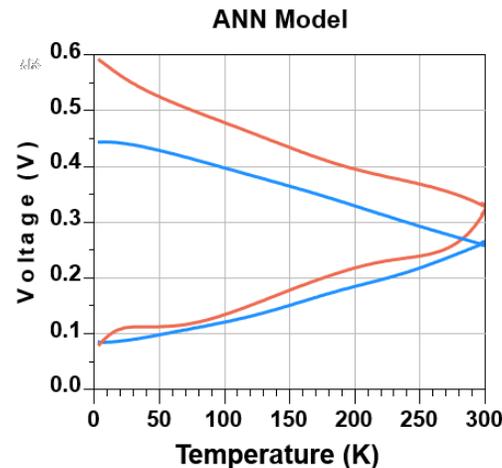
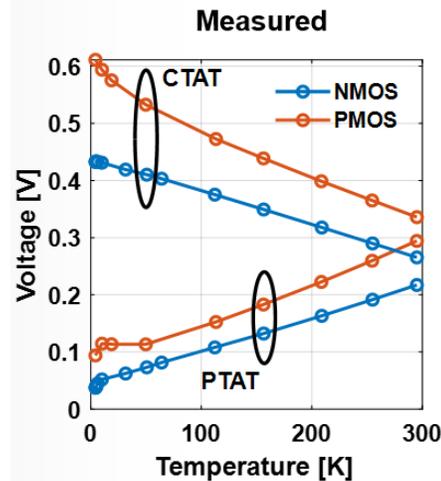
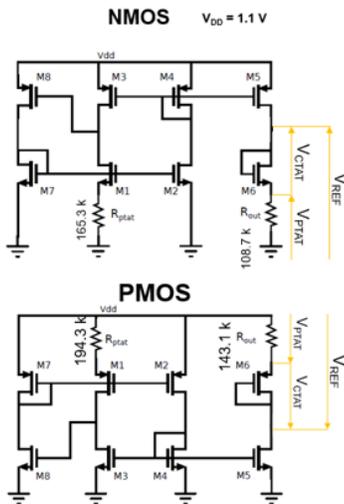
Cryogenic CMOS Modeling

Enabling circuit simulations for quantum control applications

$$I_d = I_d^{ANN}(V_g, V_d, T, W, L)$$

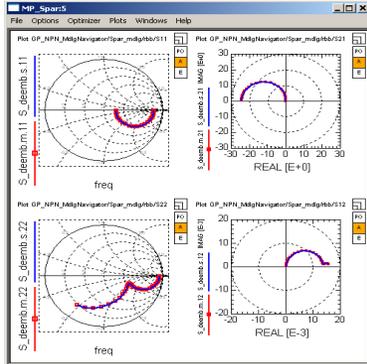
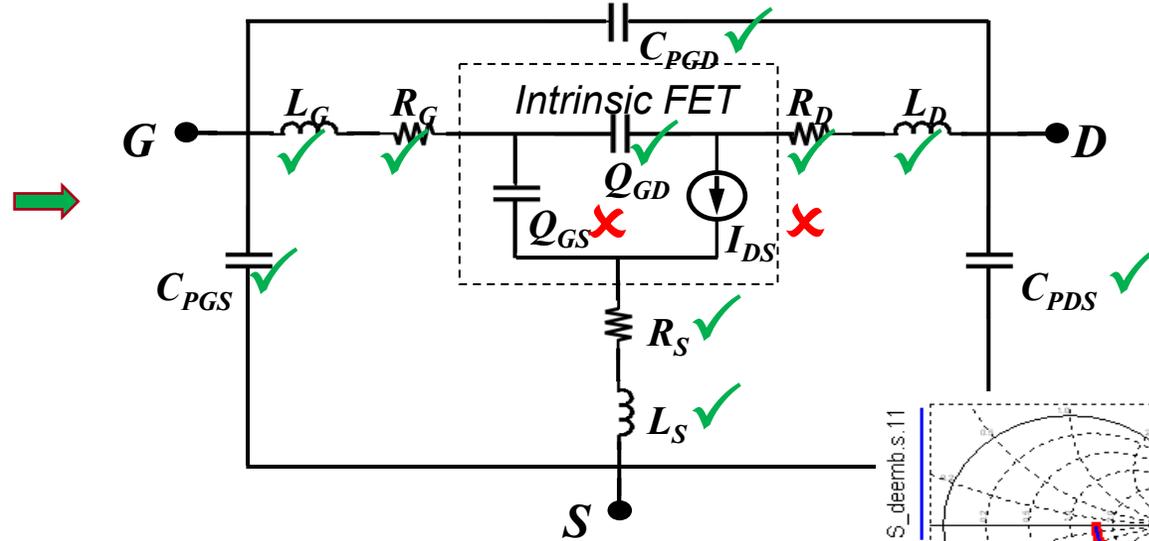
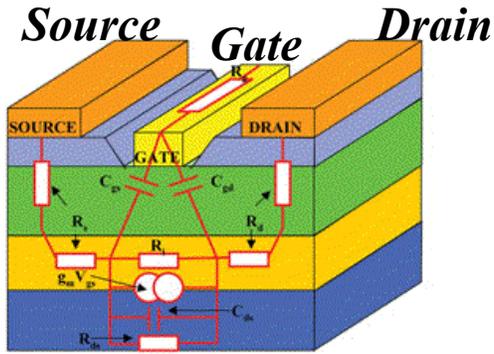


Voltage Reference Circuits



P. A. Hart, J. van Staveren, F. Sebastiano, J. Xu, D. E. Root and M. Babaie, "Artificial Neural Network Modelling for Cryo-CMOS Devices," 2021 IEEE 14th Workshop on Low Temperature Electronics (WOLTE), 2021, pp. 1-4, doi: 10.1109/WOLTE49037.2021.9555438.

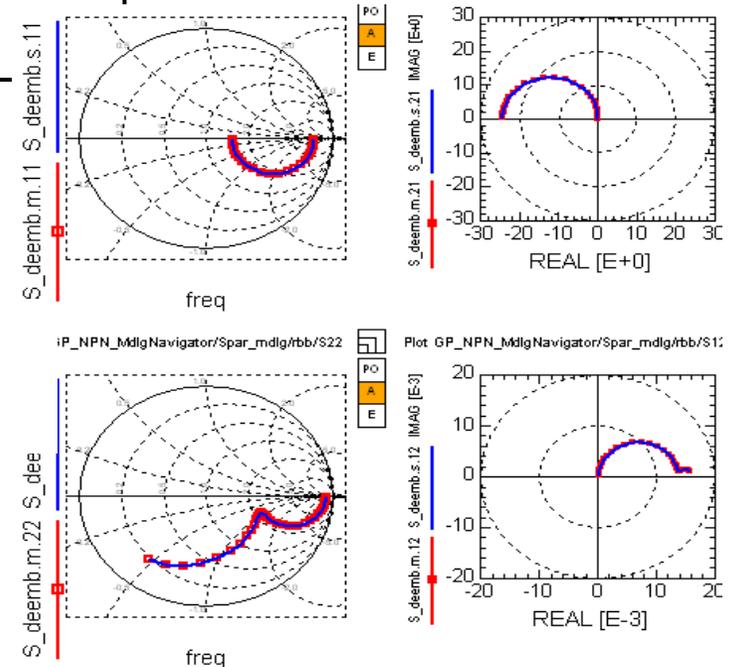
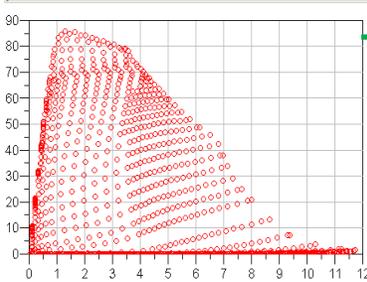
Nonlinear building blocks for device models – Hybrid modeling solution



ANN Training

$$Q_{GS} = f_{ANN}(V_{GS}, \omega)$$

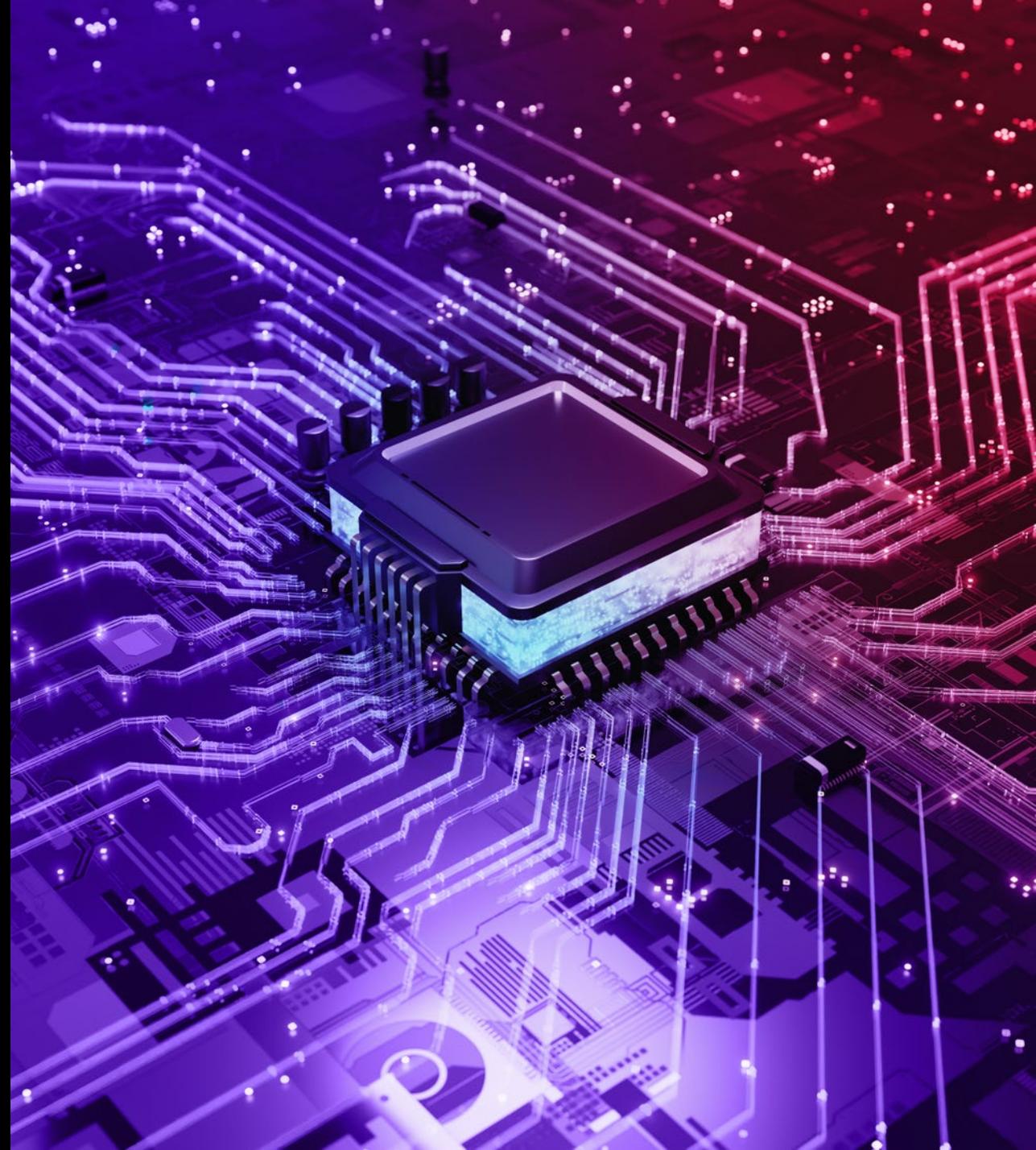
$$I_{DS} = f_{ANN}(V_{GS}, V_{DS}, \omega)$$



Circuit & Package Level

Key Challenges

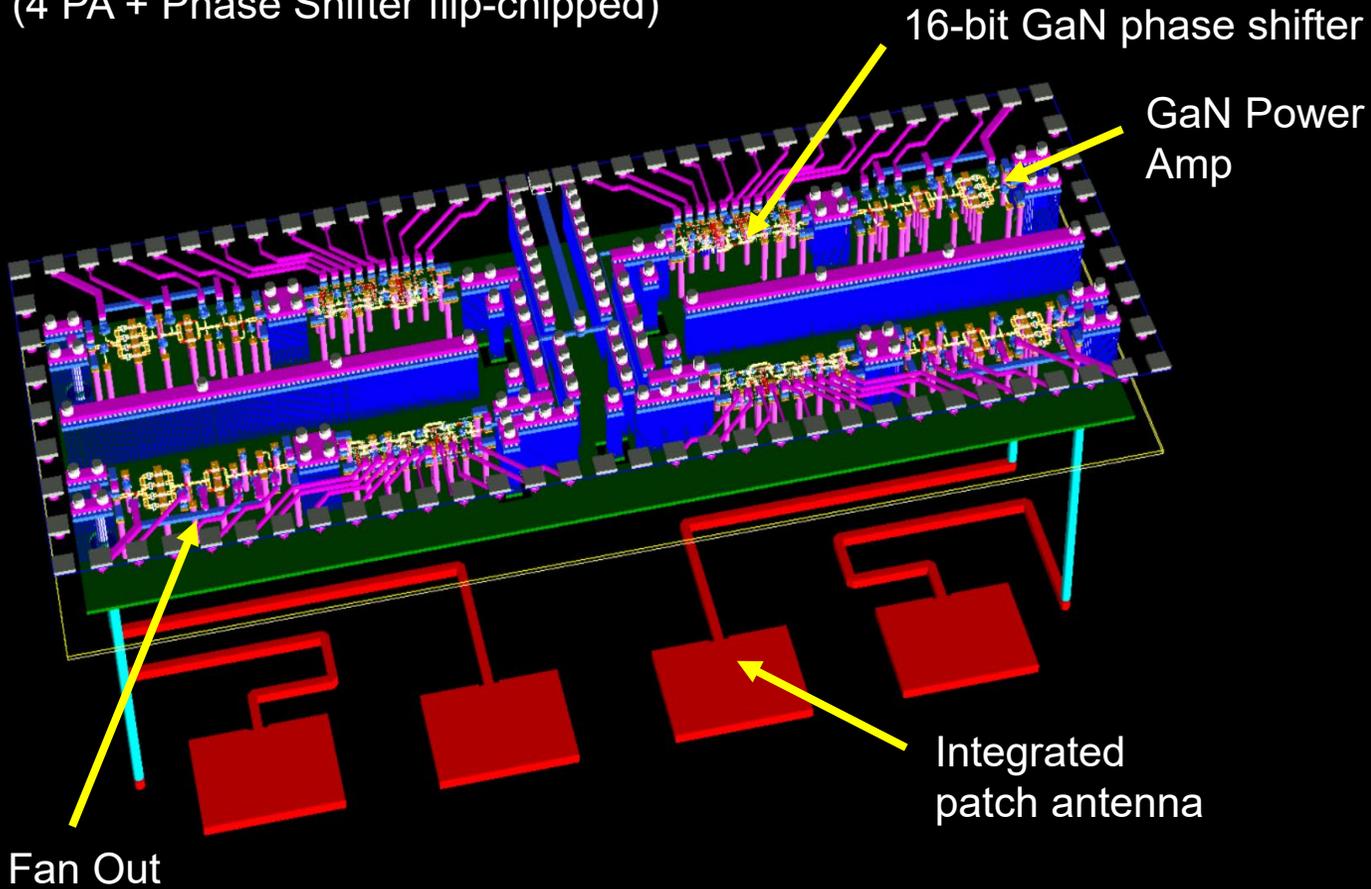
- Increasing complexity around system integration, including mixed fabrication technologies – heterogenous integration (3DIC / 3DHI)
- Assembling multi-technology structures and performing simulations across technology boundaries
- Multi-physics are increasingly relevance for overall performance



High Frequencies Drive

→ New Engineering Challenges

3DHI example of a 28 GHz Front-End module
(4 PA + Phase Shifter flip-chipped)



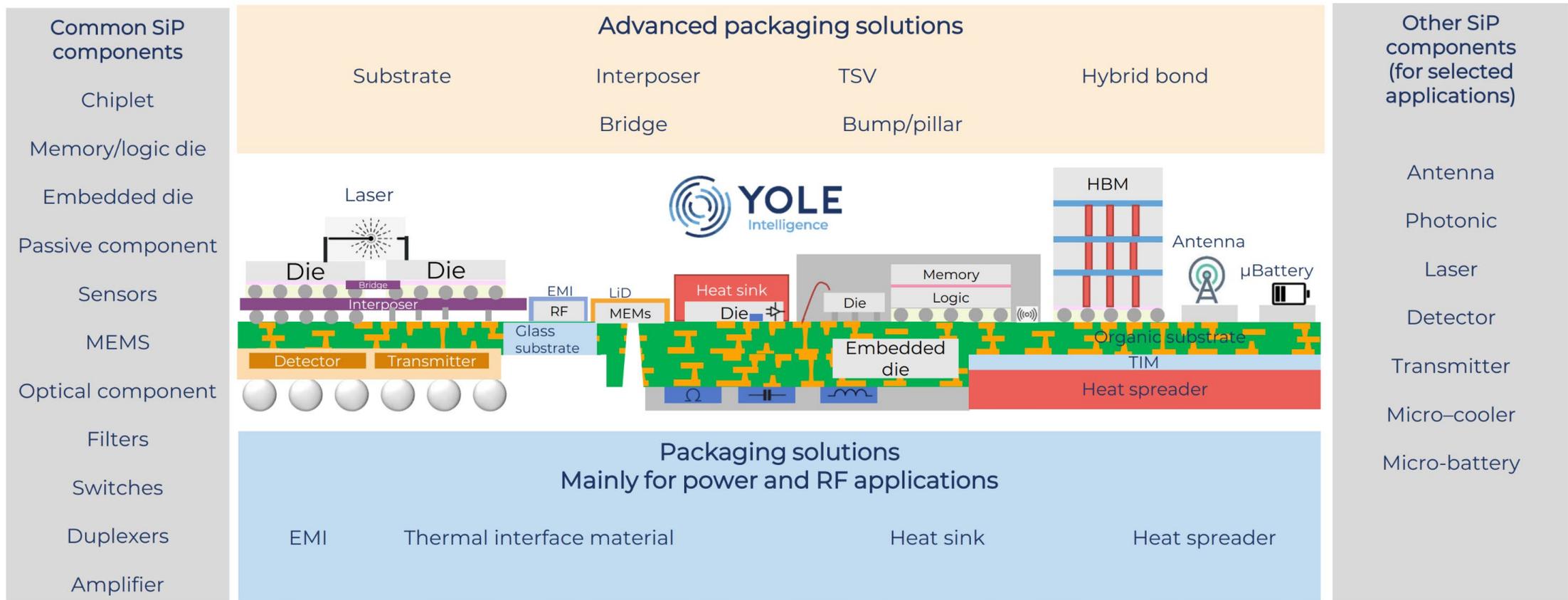
Co-Simulation Needs

- IC, Package and board-level **EM** interactions
- IP manufacturing **variations**
- **Electro-thermal** effects like self-heating

System-in-Package (SiP) – Integration Overview

YOLE Intelligence Report: Status of the Advanced Packaging Industry 2024

SiP is an integration of different components (active or passive) using a packaging solution



This diagram does not show the actual dimensions and construction – only an illustration of possible integration in a SiP.

Harder Specifications

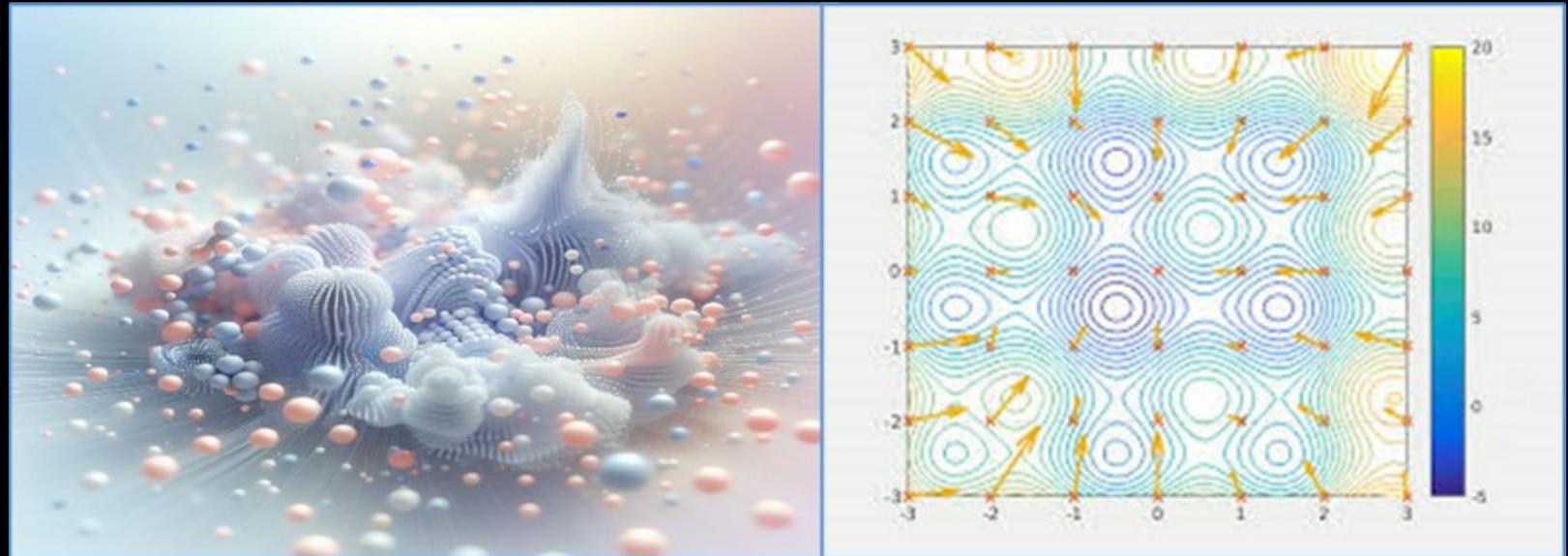
Example of Microchip SST12LP14

Features

- **High Gain:**
 - Typically 30 dB gain across 2.4~2.5 GHz over temperature 0°C to +80°C
- **High linear output power:**
 - >26.5 dBm P1dB
 - Meets 802.11g OFDM ACPR requirement up to 23 dBm
 - Added EVM ~4% up to 20 dBm for 54 Mbps 802.11g signal
 - Meets 802.11b ACPR requirement up to 24 dBm
- **High power-added efficiency/Low operating current for both 802.11g/b applications**
 - ~22% @ $P_{OUT} = 22$ dBm for 802.11g
 - ~26% @ $P_{OUT} = 23.5$ dBm for 802.11b
- **Built-in Ultra-low I_{REF} power-up/down control**
 - $I_{REF} < 4$ mA
- **Low idle current**
 - ~60 mA I_{CO}
- **High-speed power-up/down**
 - Turn on/off time (10%~90%) <100 ns
 - Typical power-up/down delay with driver delay included <200 ns
- **High temperature stability**
 - ~1 dB gain/power variation between 0°C to +80°C
 - ~1 dB detector variation over 0°C to +80°C
- **Low shut-down current (< 0.1 μ A)**
- **On-chip power detection**
- **25 dB dynamic range on-chip power detection**
- **Simple input/output matching**
- **Packages available**
 - 16-contact VQFN (3mm x 3mm)
 - Non-Pb (lead-free) packages available



Enlarge Optimization Space



Representation of a search domain of an optimizer

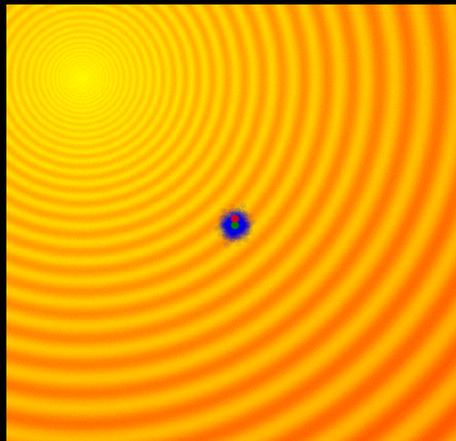
Contour plots of an optimization domain. A lot of local minima to get trapped into...

ML Optimization – a new generation of algorithms

Breakthrough techniques unlock a proven concept

Challenge

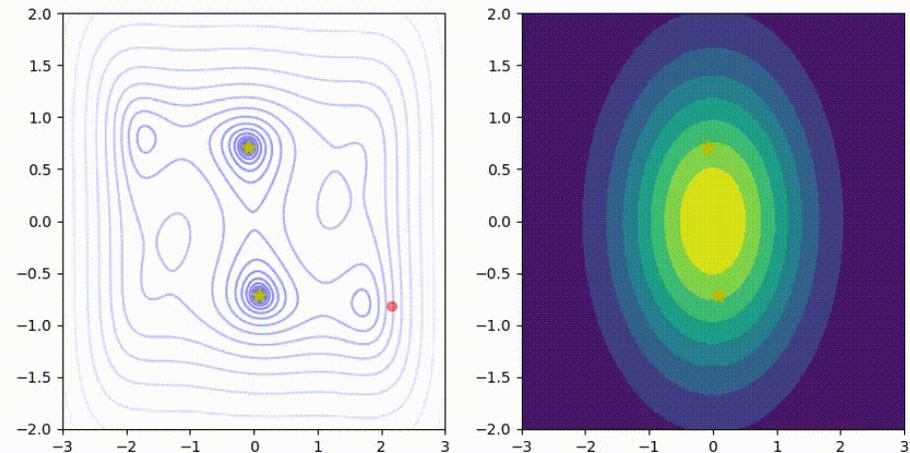
- **Conventional optimizers** struggle when handling more than **20 variables** and/or objectives/goals
- Result: Users need to work around limitations.
→ **Manually break** into many smaller problems



Older fixed Gaussian distributions try within a circle of predictions

Solution

- Use new AI/ML-driven optimization techniques:
 - Expanded capacity to **handle 40+ parameters, multi-objectives**
- Able to automate complex processes, accelerating workflow
 - Creation of **Agents** and **Agentic workflows**



AI/ML approaches are smart and adaptive, supporting higher optimization dimensions

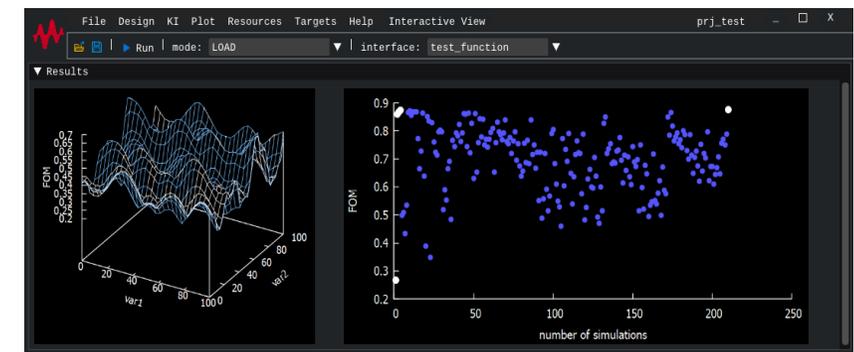
AI/ML – a new generation of algorithms

ML Optimizers especially shine when:

- There is **no historical data** — cannot apply supervised/unsupervised Machine Learning algorithms
- **Limited** number of **iterations** (less than 10K) — cannot apply Reinforcement learning
- Can utilize **Deep Learning (DL)** approaches

Re-enforcement Learning (RL) algorithms:

- **Transfer learning** capabilities with accelerated learning
- Can be **combined** with **DL** as pre-training
- Simultaneously processes hundreds of design configurations using proprietary **multi-thread** technology



ML Optimization – Applied to Complex Verifications

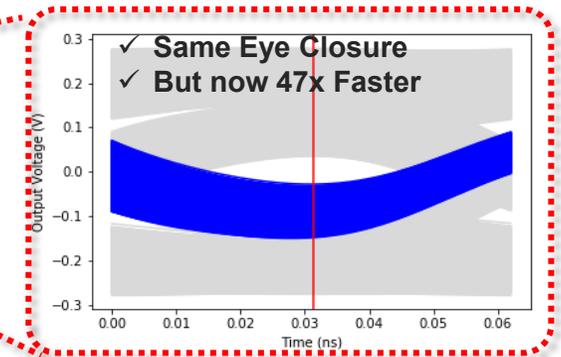
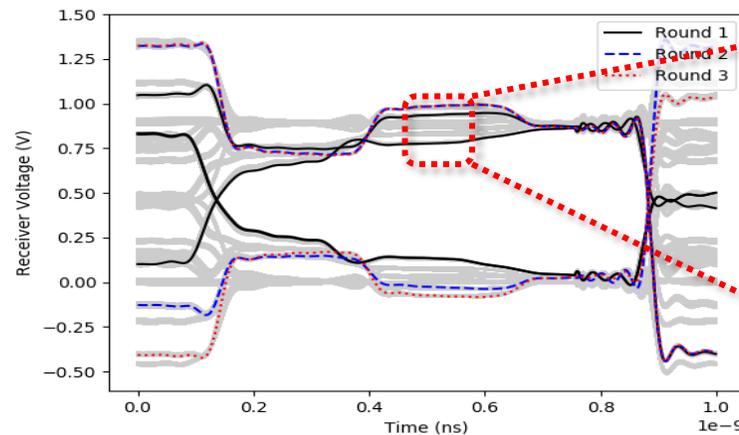
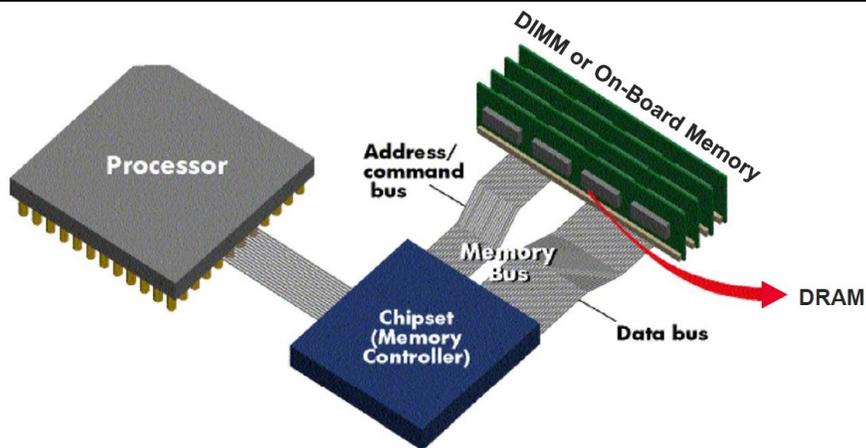
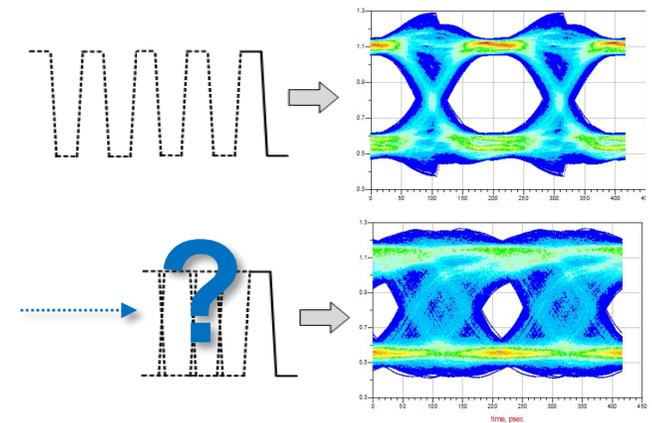
Example: Worst-case Eye Pattern for HSD/Signal Integrity applications

ML Optimization toward a maximal aggressor waveform

- Finds the **worst-case Eye Diagram**, using << shorter bit sequence, in the fewest # of Transient search simulations
- *Result:* Dramatic simulation speed-ups with optimized waveform

ML optimization for the Equalizers to clean up Eye Closure in ADS

M. Ahadi, et. al., IEEE TEMC, V. 63. N. 1, 2020



	Eye height (mV)	Eye width (ps)	Number of bits
Worst-eye	639	745	5,760
Transient Eye	639	744	1,000,000

System Level - Wireless

Key Challenges

- High-fidelity modeling requires **system architecture**, **DSP / baseband algorithm** development, and **RF system design**
- Accurate digital twin system models **require integrated scenario- modeling** and network simulation



AI is Transforming the 6G Air

New development environments needed to enable 6G

- 6G is **transitioning** from fixed/allocated assets to optimized, **reconfigurable Physical Layer (PHY)**
- **Systems** are increasingly **autonomous**, using advances in AI/ML
- **RF Hardware** will need to accommodate **dynamic adaption**: Freq, BW, MIMO, more

Initial Set of 3GPP AI/ML Use Cases and Work Items: 3GPP TR 38.843



Channel feedback

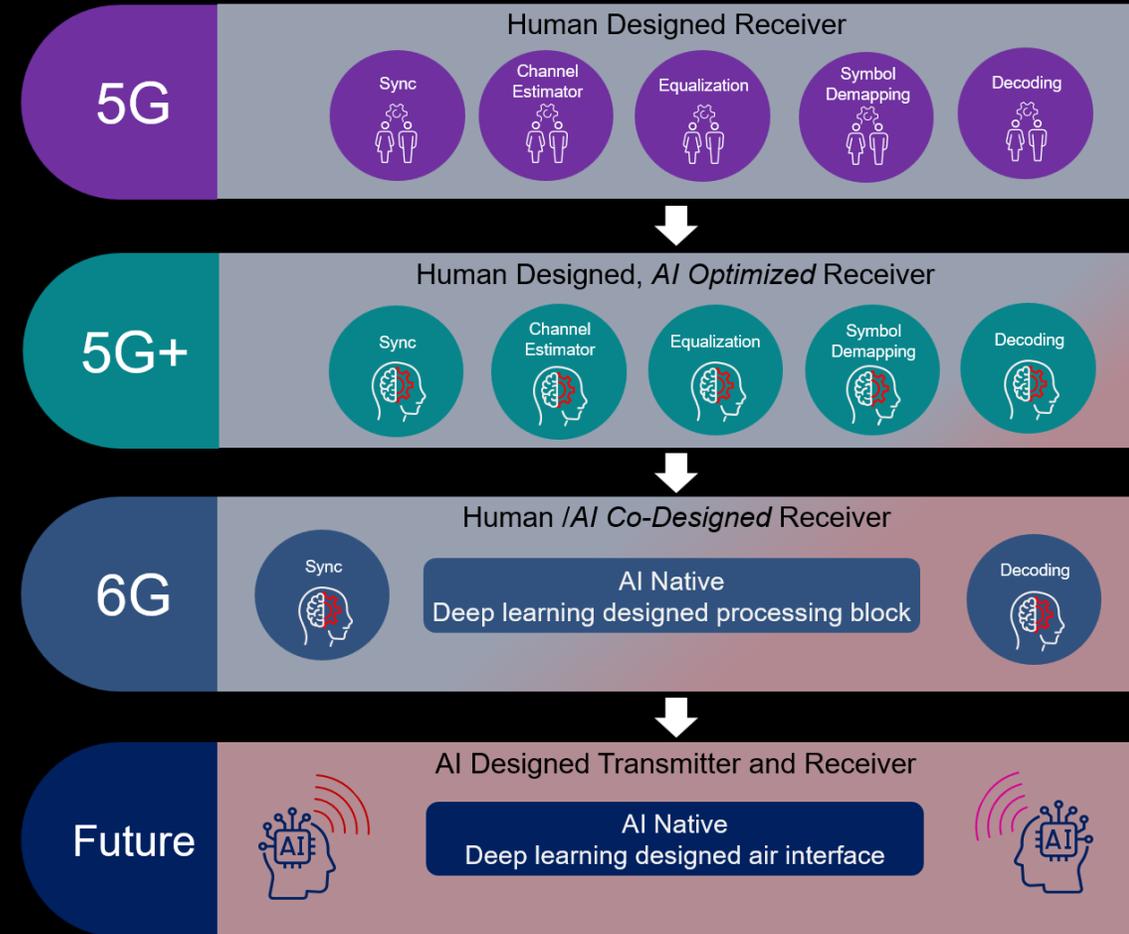


Beam management



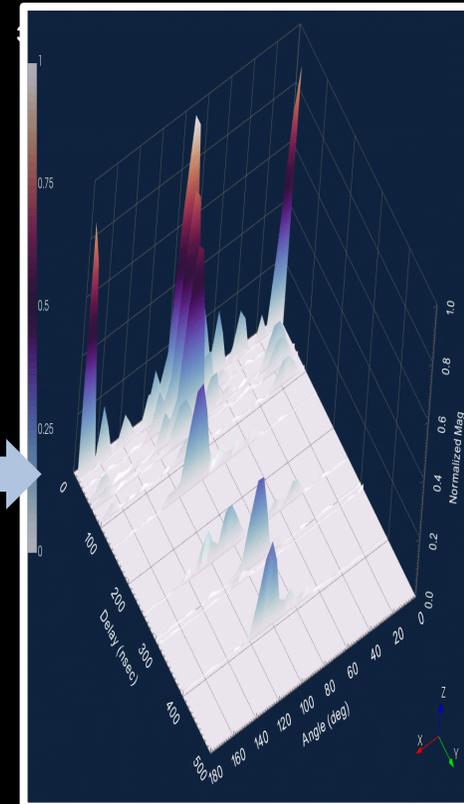
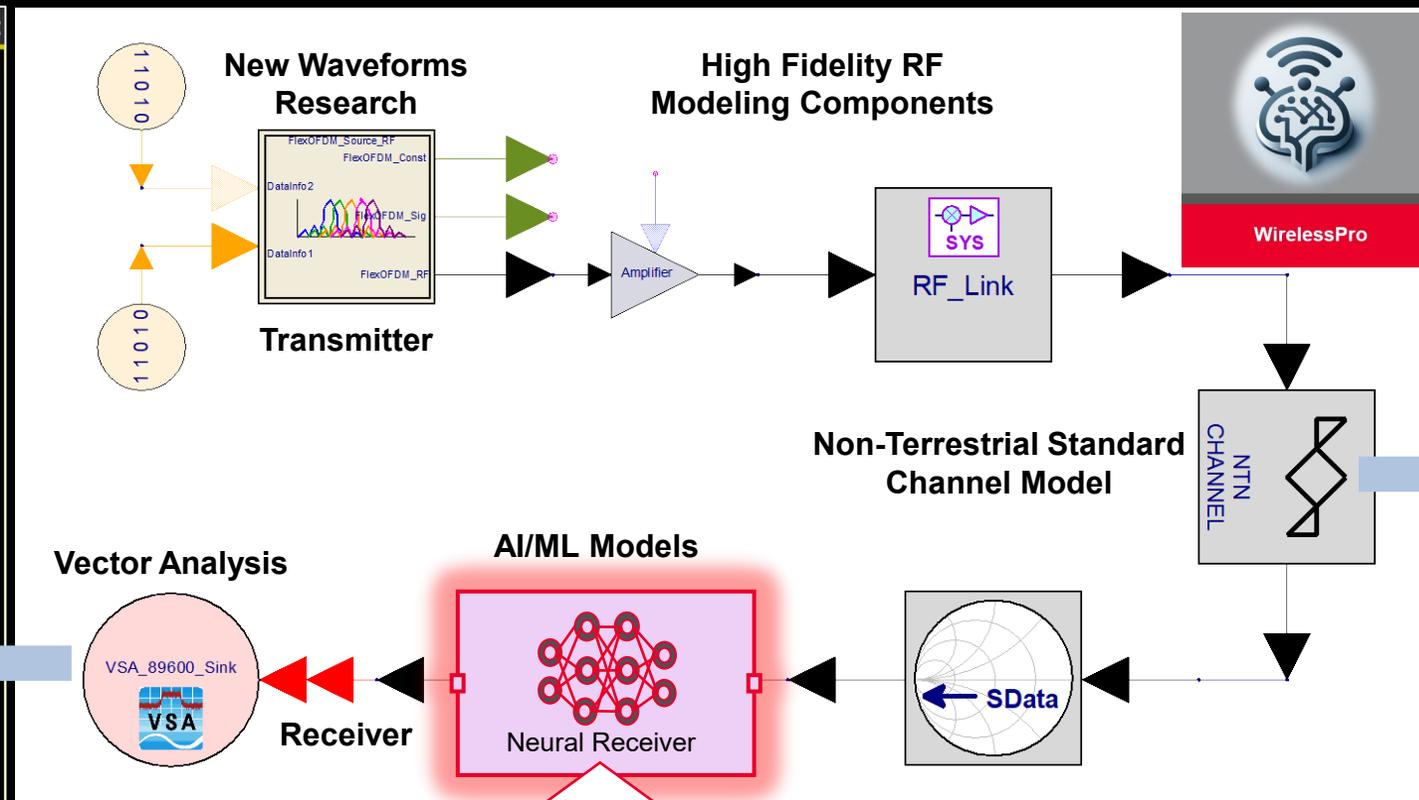
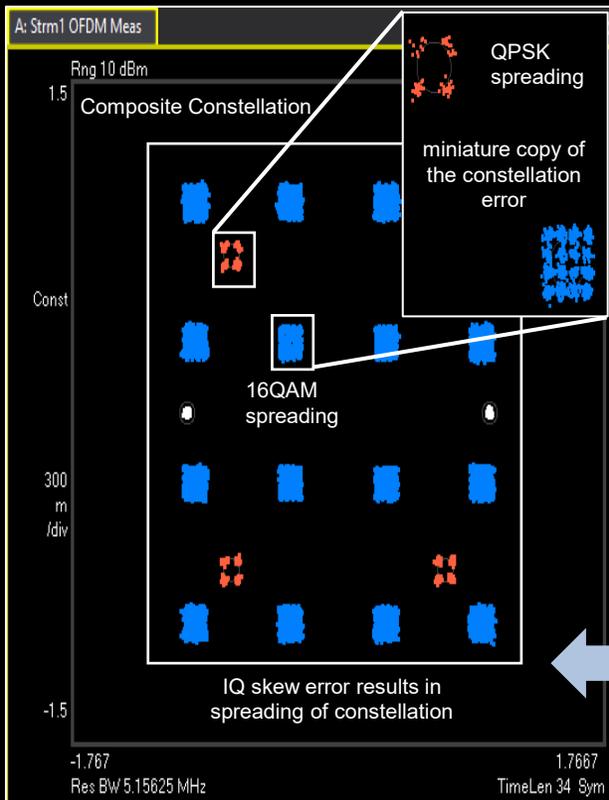
Precise positioning

Face

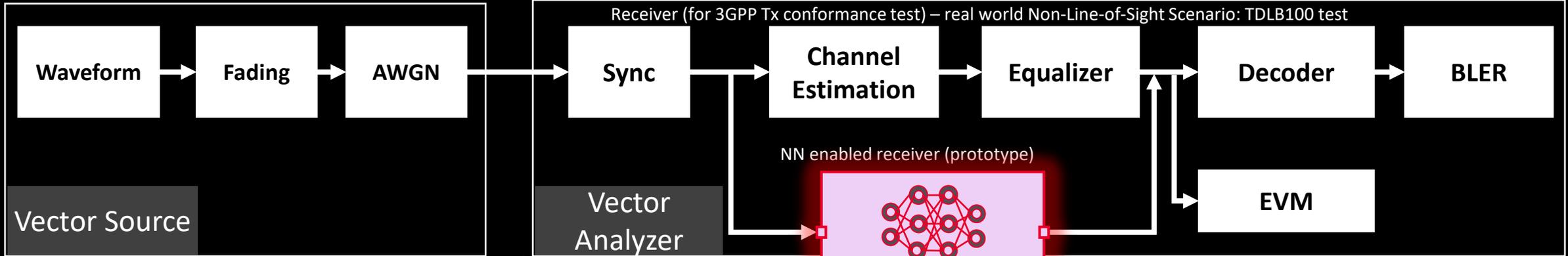


6G AI/ML Air Interface Research Enabled by Keysight EDA

Digital Twin for 6G Communications – Integrated Baseband, RF, and THz Channel + AI Receiver



Wireless NN Receiver Deployed in a Real Hardware System



Fader = OFF
AWGN = OFF



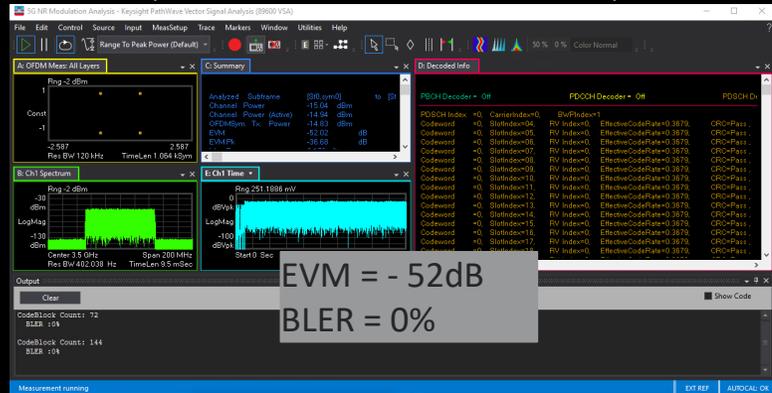
Fader = ON (TDLB100)
AWGN = ON (SNR 20dB)



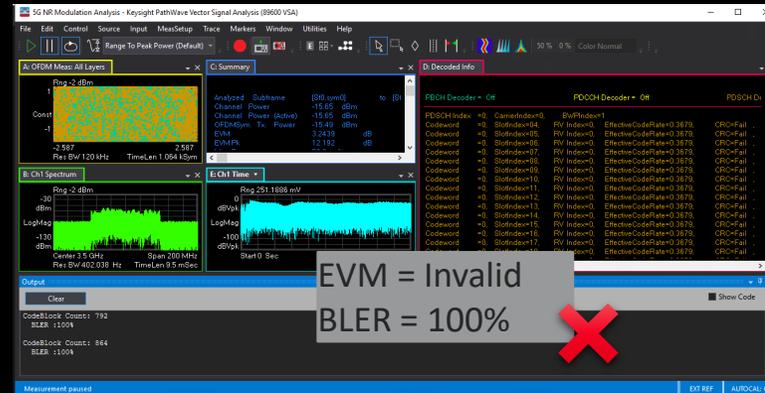
Fader = ON (TDLB100)
AWGN = ON (SNR 20dB)



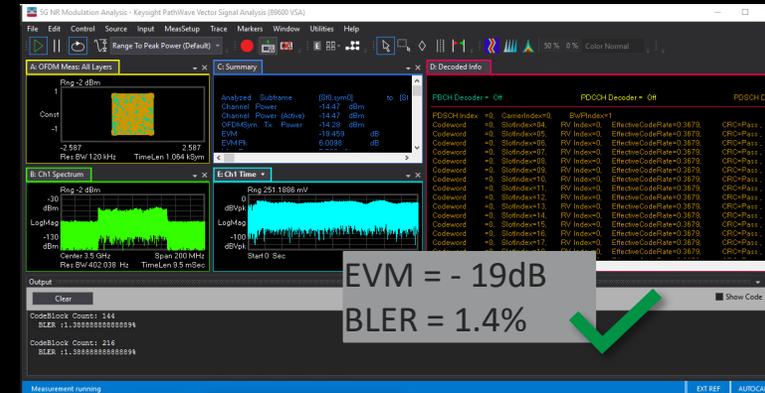
Receiver (for 3GPP Tx conformance test)



TDLB100 conformance test – No NN



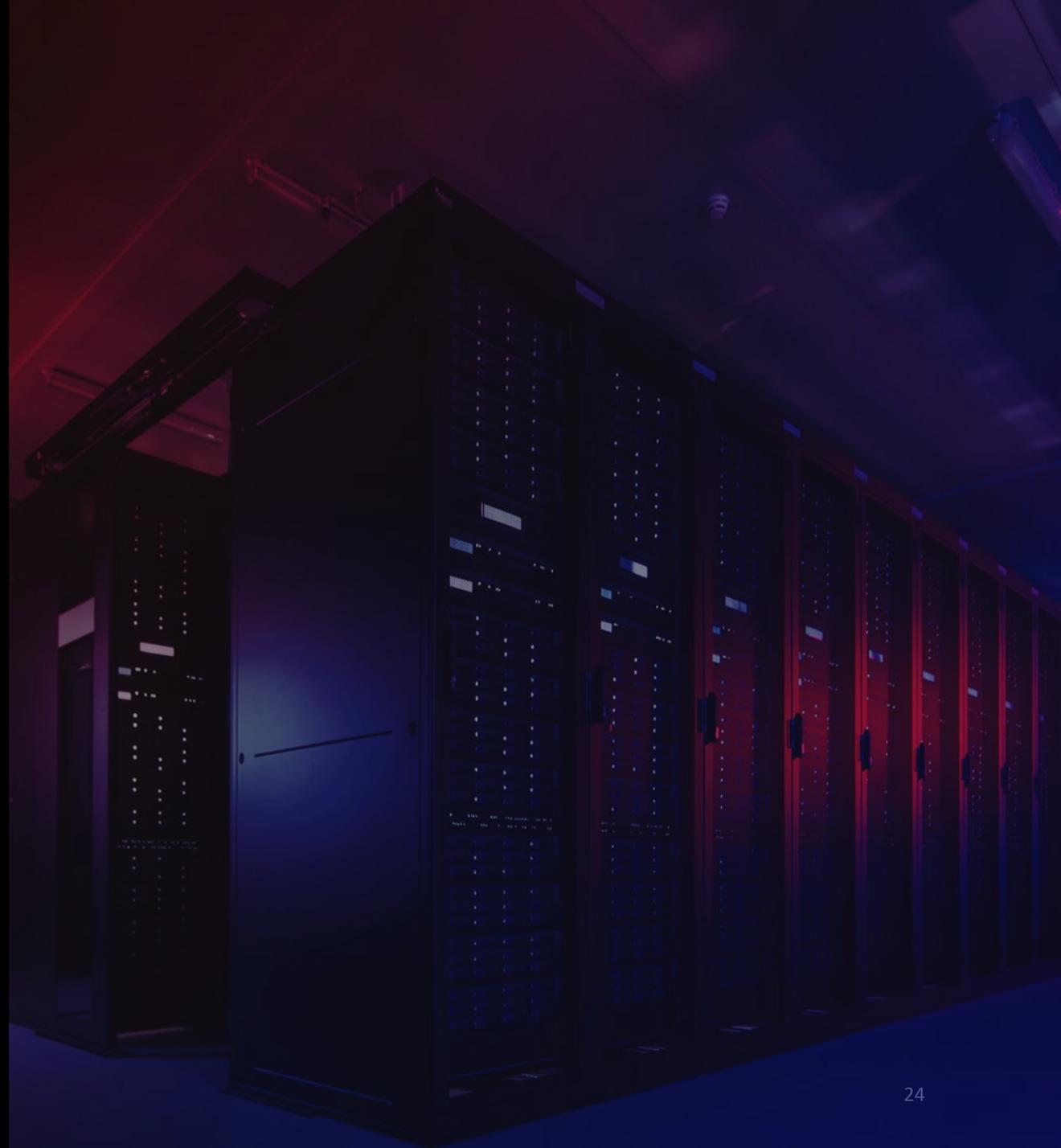
NN enabled receiver



System Level - Wired

Key Challenges

- **Metal interconnects** have reached their speed and capacity limits
- Datacenters need to **connect thousands of GPUs** to scale for AI load
 - **HPC speed up scales logarithmic, latency is critical**
 - **Ethernet standards** are evolving to support larger bandwidth and Bitrates for AI workload

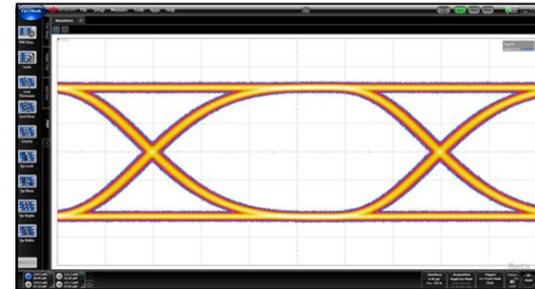
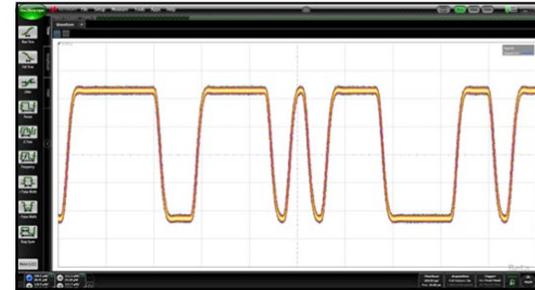


Modulation Schemes Evolve

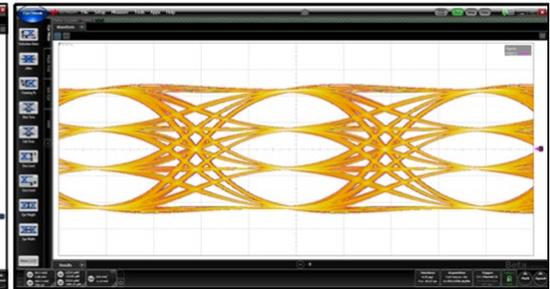
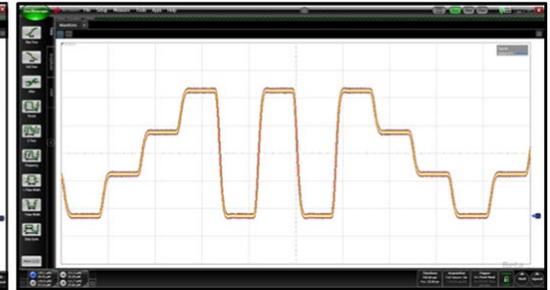
Advanced Modulation and Coding Challenges

- PAM2 (NRZ) backbone of PCIe Gen1-5 & Ethernet 802.3 – 100G
 - Better noise margins but lower bandwidth
- PAM4 standard for **200G, and 400G Ethernet, PCIe Gen 6, and future Gen 7**
 - Signals use **four amplitude/voltage** levels, **doubling the data rate (Bits)** in the same bandwidth as NRZ
- PAM4 requires sophisticated signal integrity management due to reduced noise margins

NRZ (PAM2)



PAM4



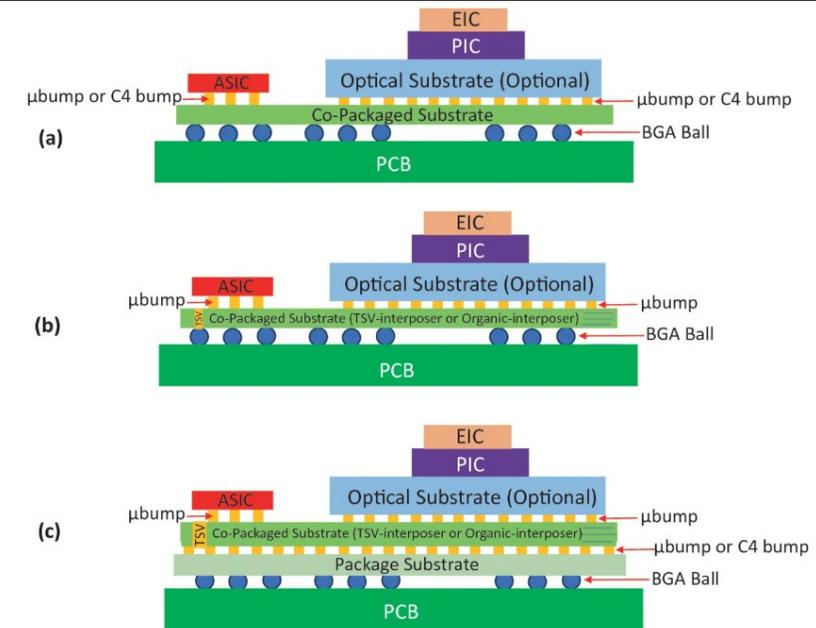
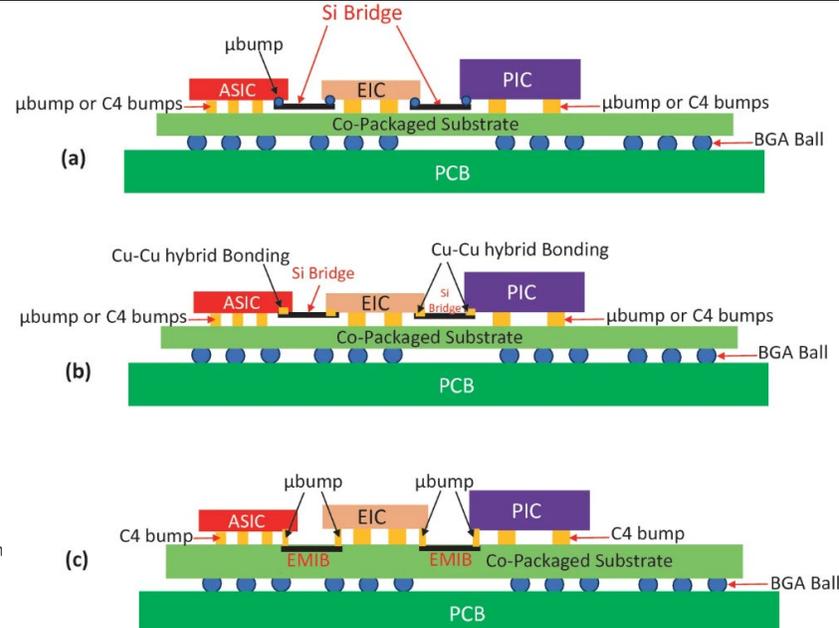
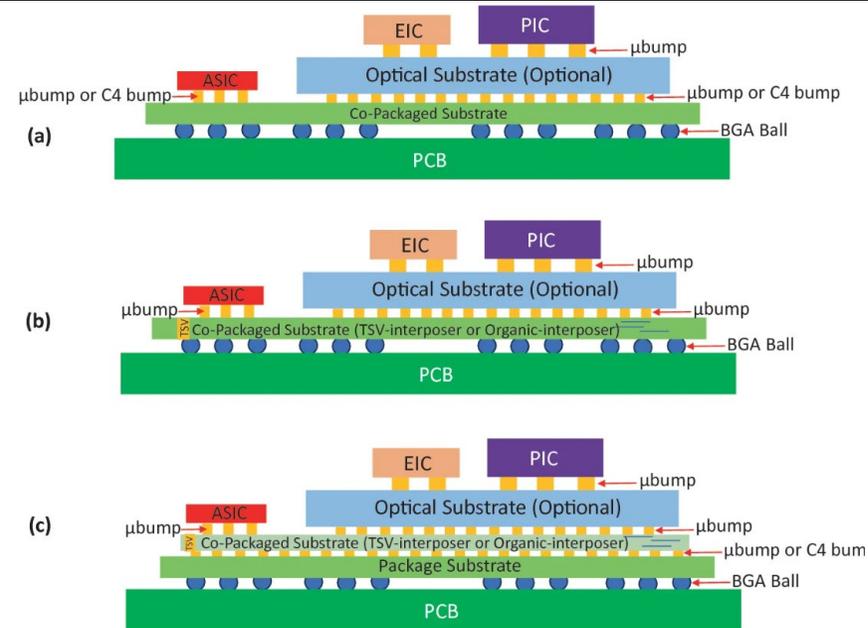
Feature	PAM2 (NRZ)	PAM4
Bits per symbol	1	2
Voltage levels	2	4
Noise margin	High	Lower
Complexity	Low	High
Use cases	PCIe Gen 1–5, USB	PCIe Gen 6+, 400G Ethernet, Data Centers

Technology integration needed to support HPC and PAM4 requirements

2D Heterogeneous Integration of ASIC Switch, PIC and EIC

2D Heterogeneous Integration of ASIC Switch, PIC and EIC with Bridges

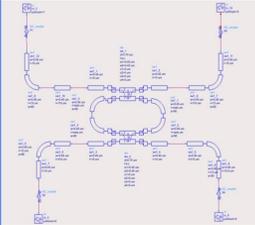
3D Heterogeneous Integration of ASIC Switch, PIC and EIC



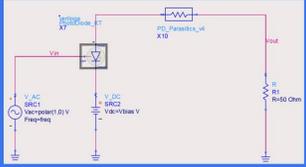
Photonic Design Solutions - Challenging

Models & Design

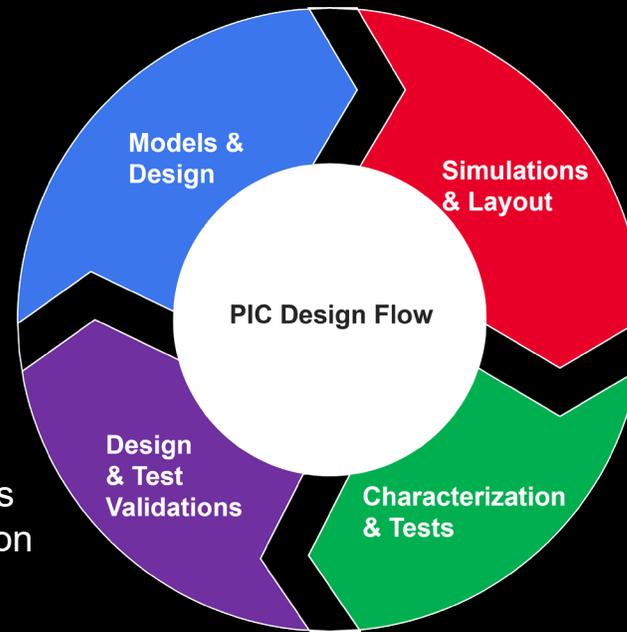
Micro Ring Resonators & Modulator



Photodetectors



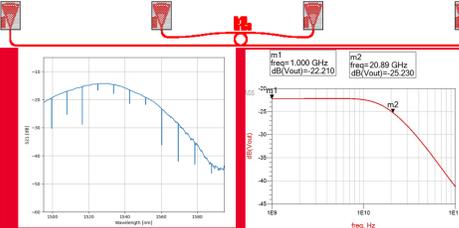
Photonic Model



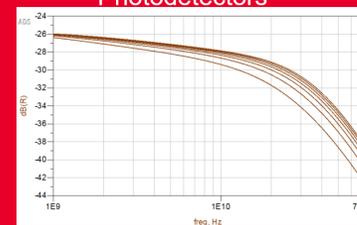
RF simulation technology and flexible workflows

Simulations & Layout

Micro Ring Resonators & Modulator

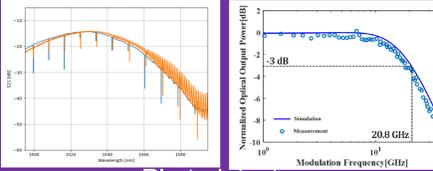


Photodetectors

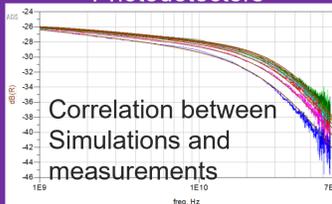


Design & Test Validations

Micro Ring Resonators & Modulator



Photodetectors



Correlation between Simulations and measurements

Photonics Verification solutions

E-O-E design, simulation and measurement flow

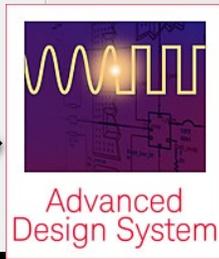
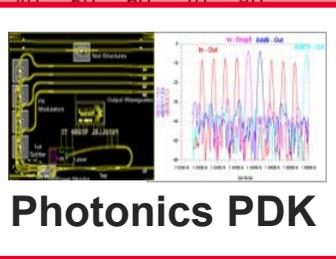
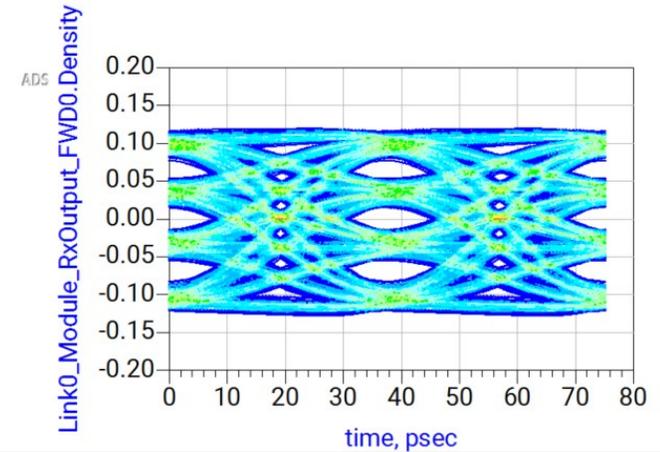
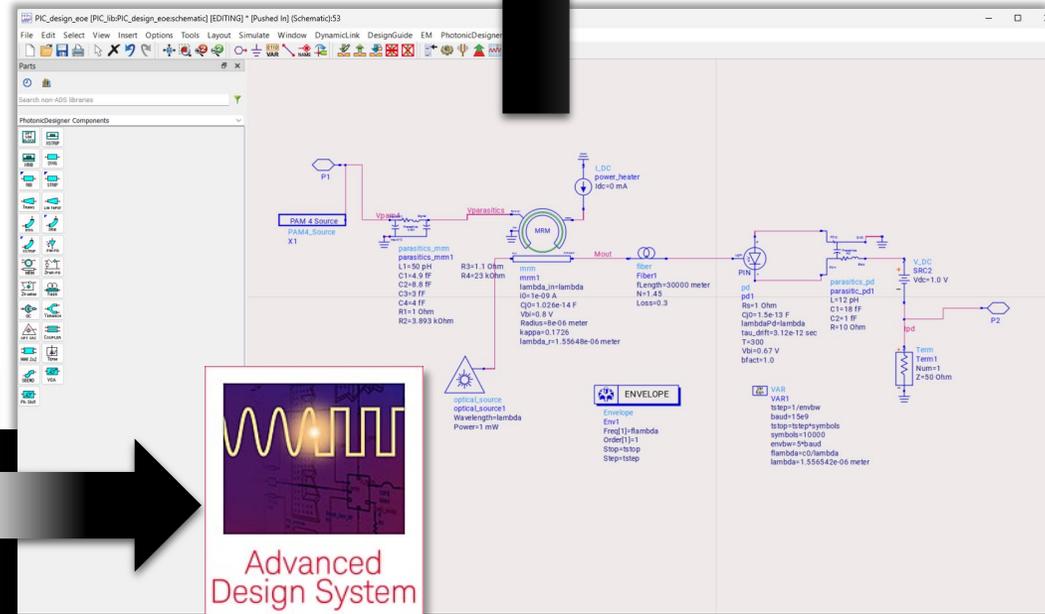
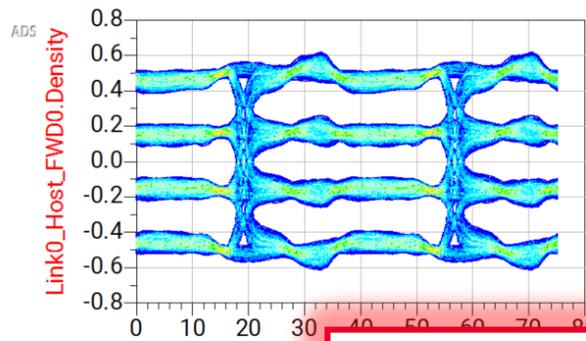
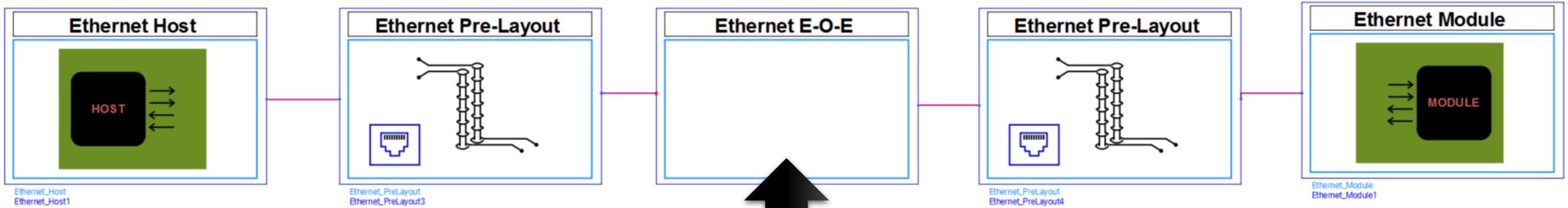
Photonic Characterization Capabilities

Characterization & Tests



E-O-E simulation for digital standards: Ethernet, PCIe

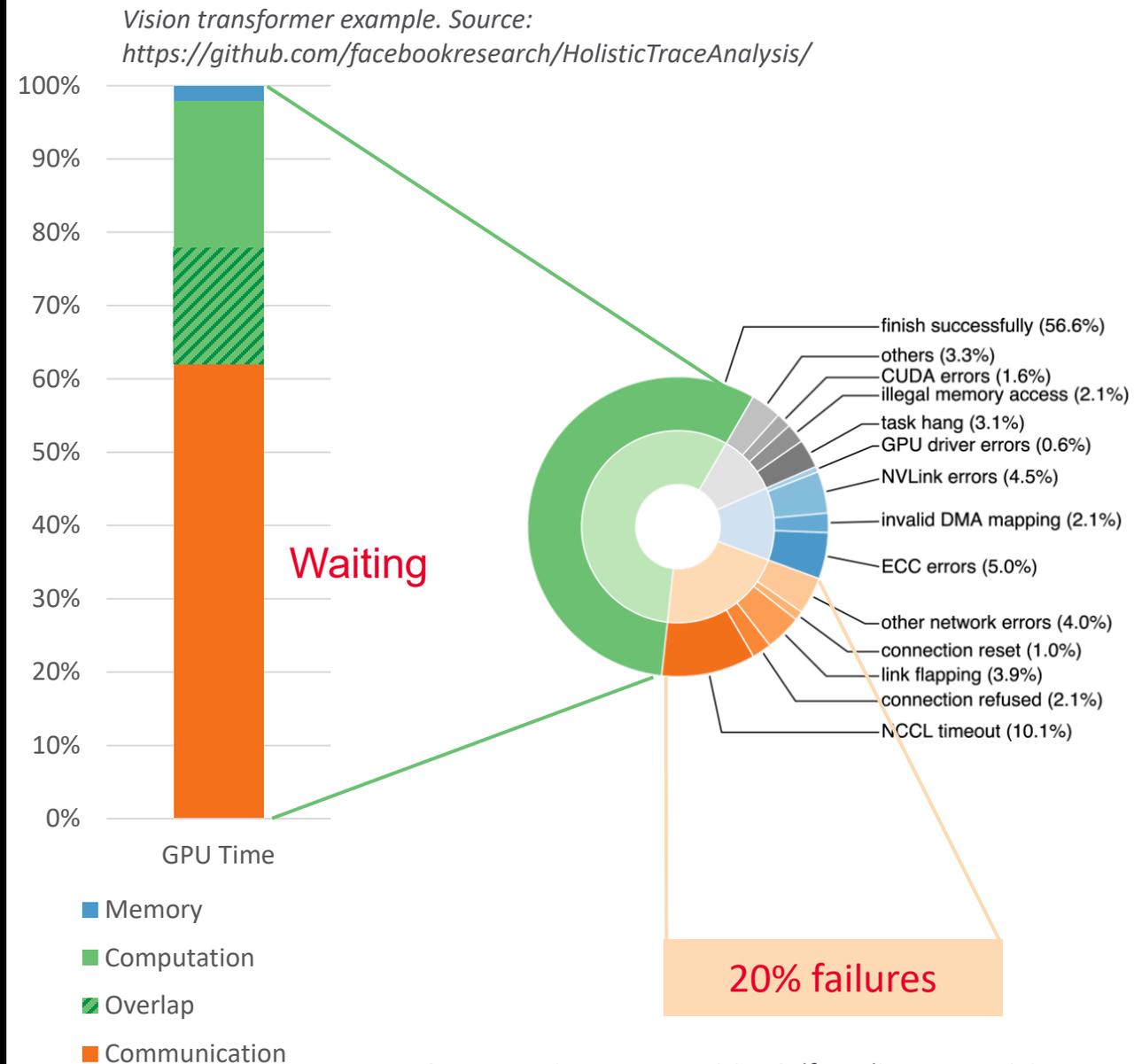
Example workflow



Datacenter Level

Key Challenges

- High networking bandwidth for AI/ML workloads
- Cost to test network designs and parameters
 - GPU Availability
 - Unique test engineering skillset for AI networks
- Time-to-market to validate AI Clusters



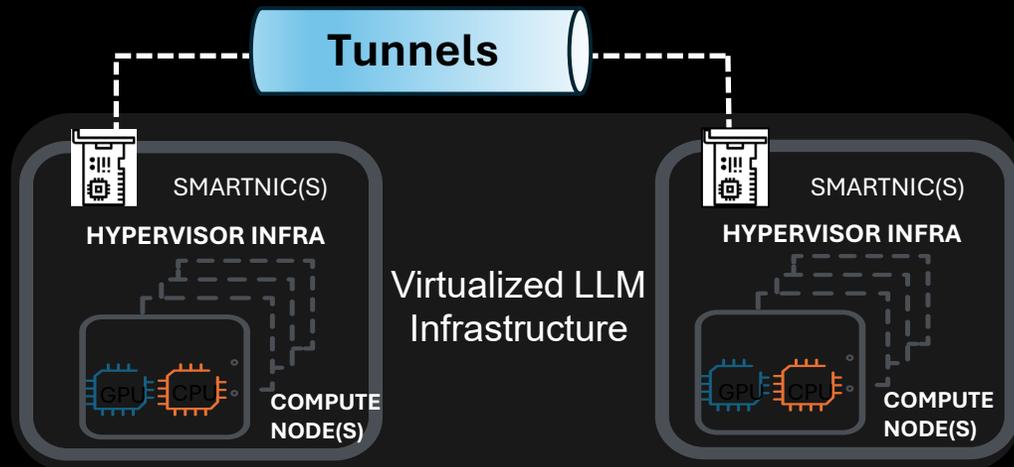
Source: *Unicon: Economizing Self-Healing LLM Training at Scale*, Tao He¹, Xue Li¹, Zhibin Wang^{1,2}, Kun Qian¹, Jingbo Xu¹, Wenyuan Yu¹, Jingren Zhou¹ ¹Alibaba Group, ²Nanjing University

Operation of AI ML Network Infrastr

re

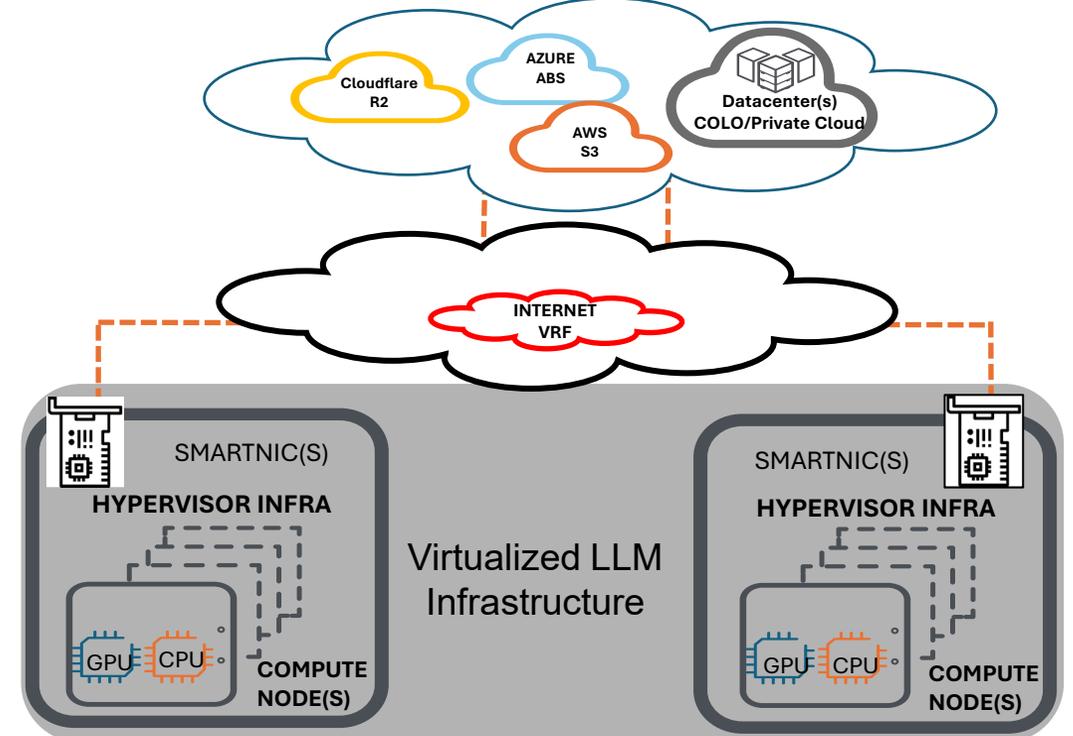
Backend Data Center for AI Models **Training** East-West Traffic Test Demands –

- **Distributed GPU/CPU architectures**
- Collective communications & parallel processing among GPU nodes
- Hyper-virtualized **infrastructures** for multi tenancy
- Immense **performance needs** for lossless connectivity and minimum tail-end latency

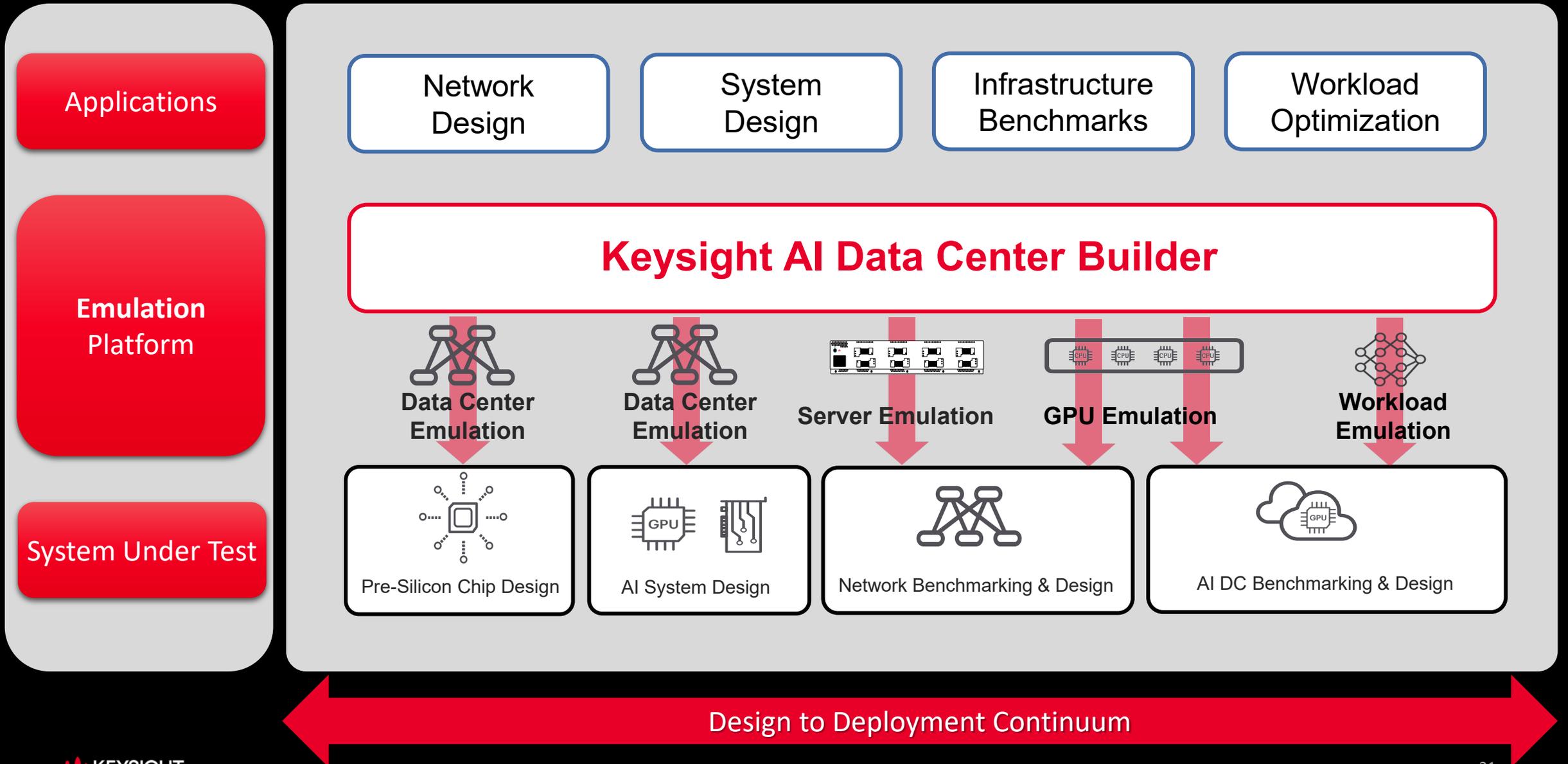


Front-end Data Center for **Inference** Workloads North-South Network Traffic Test Demands -

- **GPUs need high-speed access** to block/remote storages
- Provisions to **secure data (encrypted)** in motion
- **Ultra-low latency** demands

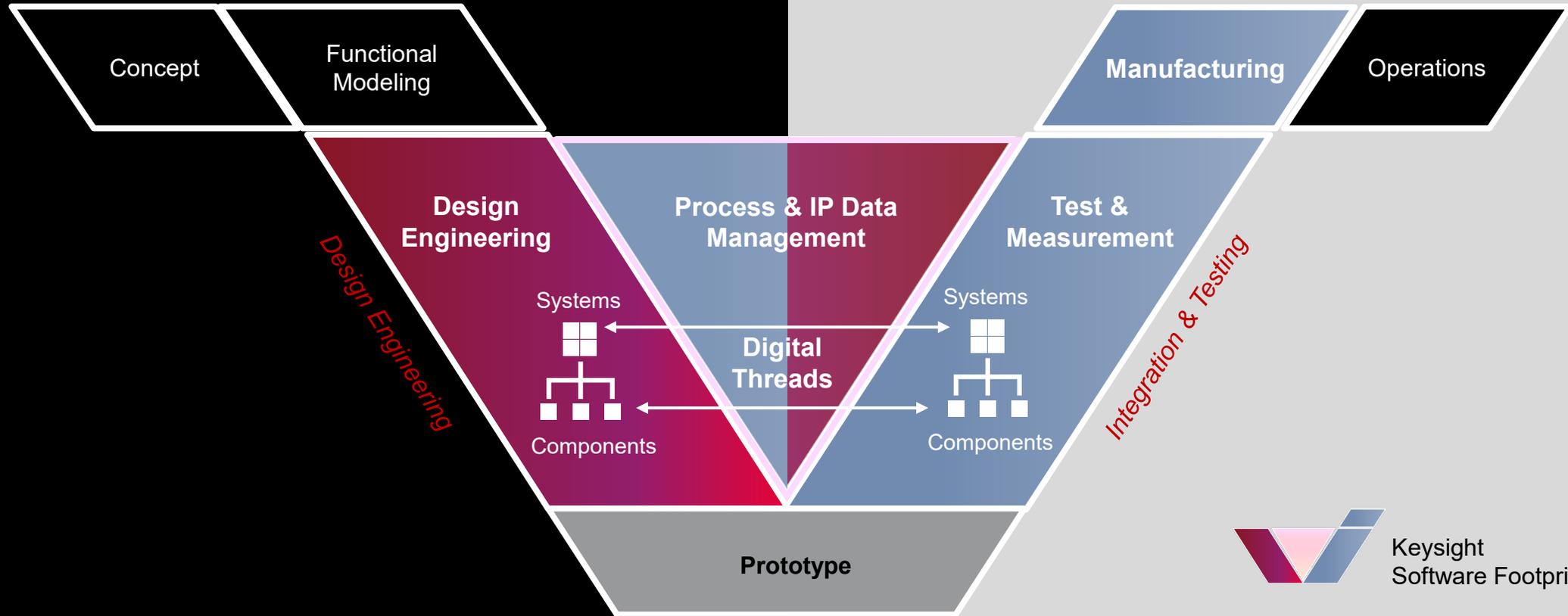


Product lifecycle & Use case Coverage



Summary - End-to-End Workflow

Design solutions with users in mind



DIGITAL TWINS

PHYSICAL SYSTEMS



Thank you